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THE DESIGN OPTIMIZATION OF INTEGRATED

BROADBAND AMPLIFIERS
by
Bruce A. Wooley

Memorandum No. ERL-M284

23 September 1970

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\text { University of California, Berkeley } \\
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## CHAPTER I

## INTRODUCTION

From an economic standpoint, the circuits best suited to monolithic realization are generally those that can be used as basic functional blocks in a wide range of electronic applications. The field of commercial analog integrated circuits is dominated by a class of circuit of this type--the operational amplifier. There are, however, a number of analog functions, with widespread applications, that cannot be realized effectively with such multipurpose circuits; one of these is broadband lowpass amplification. The bandividths that can be achieved using operational amplifiers are typically two or more orders of magnitude below those obtainable with amplifier designs intended specifically for broadband performance. For this reason, broadband lowpass amplifiers have emerged as a separate class of single-purpose linear integrated circuit.

In the design of integrated circuits, it is highly desirable to maximize the range of performance specifications that can be met with a single design. For this reason, an extensive design optimization effort is warranted. The emphasis of the work reported in this disscrtation is on the development and application of a practical automated design optimization procedure for monolithic broadband amplifiers.

In Chap. II, the basic problems of broadband amplifier design are introduced, and a subclass of such amplifiers is defined by a set of general design requirements. This subclass, namely dc-coupled integrated broadband voltage amplifiers, serves as a focus for the application of

## ABSTRACT

A circuit design automation program has been implemented to optimize the design of dc-coupled monolithic broadband amplifiers. In this program, dc conditions, device geometry, and all passive elements are adjusted to obtain the maximum small-signal -3dB bandwidth for a specified gain and quiescent power dissipation. The program is used to compare several basic configurations suitable for broadband monolithic voltage amplification by establishing optimum amplifier designs for each configuration.

The principal subsections of the design optimization program are a frequency response analysis subroutine, a subroutine for determining response sensitivity, and a subroutine for minimizing a scalar function of several variables. The circuit analysis is formulated on a nodal admittance matrix basis and the results are used to generate a scalar index of performance. The gradient of this index is then evaluated from analysis of the response sensitivity to circuit elements. The adjoint network approach is uscd for this sensitivity analysis. The subroutine for minimizing the performance index is based on the Fletcher-Powell algorithm.

The design program is used to optimize eight complete differential amplifiers developed from basic feedback configurations that are suitable for voltage amplification in integrated circuits. A voltage gain of 34 dB and a power dissipation of 96 mW , with $\pm 6 \mathrm{~V}$ power supplies, are specified for the complete amplifiers. The optimization criterion is to achieve the maximum $-3 d B$ bandwidth obtainable without peaking. The results of the
design optimization procedure are used to compare the effectiveness of the basic feedback configurations considered. The best overall performance is obtained for the amplifier based on a series-shunt feedback pair with an emitter-follower included within the feedback loop. This amplifier achieves a bandwidth of 123 MHz for devices with a typical $f_{T}$ of 580 MHz at collector current of 1 mA . The input resistance of the amplifier is $850 \mathrm{k} \Omega$, the first-order gain variation over the temperature range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ is $.6 \%$. The predicted drift in the de output level over this temperature is 30 mV , and the available output voltage is $\pm 2.4 \mathrm{~V}$ for $\pm 6 \mathrm{~V}$ supplies.

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the design procedures to be described. Basic amplifier configurations suitable for meeting the set of design requirements are also introduced in Chap. II.

In Chap. III, a program for optimizing the design of broadband amplifiers is described. This program significantly increases the number of available degrees of frcedom that can be utilized in achieving an optimum design. The program adjusts dc biasing conditions, device geometry, and all passive elements to optimize the small-signal amplifier response. In the work described here, the optimum is defined as the maximum smallsignal bandwidth consistent with a specified low-frequency gain and total quiescent power dissipation.

The circuit modeling used in the design optimization procedure is described in Chap. IV. The form of the assumed device structure is presented along with an appropriate small-signal transistor model. The model is characterized on an experimental basis for a typical bipolar integrated circuit processing schedule.

In Chap. V, complete amplifier designs are developed from the basic configurations introduced in Chap. II. Optimum designs are established for each of these amplifiers and are presented in Chapter VI. These designs are used to compare the relative effectiveness of the basic configurations. In Chapter VII, the performance of discrete component and monolithic amplifier realizations is described.

## CHAPTER II

TIIE BROADBAND AMPLIFIER PROBLEM

### 2.1 Limitations on Performance and Design

The frequency response of a broadband amplifier is limited essentially by the charge storage in active devices and parasitic elements. As a result, a relatively complex circuit model is needed for precise analysis of the response. The nonautomated design of such amplifiers, therefore, usually entails severe analytical approximations and extensive experimental work.

A nonautomated design procedure, for either discrete component or monolithic amplifiers, generally begins with an initial, somewhat arbitrary, design choice. The low-frequency characteristics may be determined precisely for this design, but a rough, first-order estimate must often be used for the bandedge response. Once the initial design choice is made, the amplifier is realized experimentally. In the case of a discrete amplifier, the final design is often arrived at simply by adjusting components of the preliminary realization. However, for monolithic amplifiers such adjustments are rarely feasible. Instead the performance of the preliminary realization is used as a basis for refining the initial analytical approximizations and establishing an improved design.

The need for preliminary experimental realizations in a conventional nonautomated design procedure can be eliminated by using precise frequency response analysis to refine the initial design choice. Because of the high cost associated with realizing an integrated design prototype, this substitution of precision analysis for experimental work represents a significant
advantage in design of monolithic amplifiers. The improved analysis capability required for such a substitution is provided by computer-aided circuit analysis. Through automated analysis, it is possible to analyze efficiently circuit models that accurately reflect broadband amplifier performance. Repeated analyses can be performed as a design is modified and, in effect, a scquential form of optimization can be carried out with respect to a small number of design variables.

In a nonautomated design procedure, or in a procedure where only the analysis function is automated, there is little opportunity for optimization in the design of broadband amplifiers. The complexity of the relationship between the amplifier response and the design variables precludes an algebraic approach to optimization. If computer-aided analysis is used, a limited form of optimization can be achieved. However, the procedure is usually restricted to a small number of variables that are considered sequentially, or one-at-a-time. For example, while elements in a feedback network can be adjusted to achieve maximum amplifier bandwidth, convenient but fixed, choices must be made for dc conditions and device geometry. Even with automated analysis, optimization in terms of a substantial number of the available degrees of freedom remains impractical.

To optimize the design of broadband amplifiers with respect to a large number of design parameters, it is necessary to automate a design procedure wherein the parameters are simultaneously adjusted in an iterative numerical search for an optimum. Effective means for directing such a search are available in the form of algorithms for finding the minimum of a scalar multivariable function. In this dissertation, the implementation and application of such a design procedure is presented for a particular class of integrated broadband amplifiers.

### 2.2 General Design Requirements

The class of amplifier of principal interest in this study is defined by the design requirements given in Table II.l. The first two requirements restrict consideration to circuits that are basically voltage, as opposed to current, amplifiers. Implied in these requirements is the assumption of a low source impedance (50 2), characteristic of a voltage source. A moderate gain level, in the range of 20 to 40 dB , is typical of amplifiers intended for broadband applications. The amplifier output is of a voltage source nature by virtue of the specification for low output impedance. A high input impedance is specified to minimize interaction with low impedance sources. In addition, the severe mismatching of input and output impedance levels minimizes the interaction between cascaded amplifiers, and the response of such a cascade can be accurately estimated on the basis of individual amplifier characteristics.

The third requirment of Table II.l is for a low gain sensitivity to both environment (temperature) and processing. As indicated by the next requirement, a standard, junction-isolated, bipolar transistor process is to be used. Thin-film elements are excluded from consideration.

Listed fifth in Table II.l is a requirement for dc-coupling with zero volt quiescent levels at both input and output. This requirement implies that dc level shifting must be incorporated within the monolithic amplifier; it is then possible to cascade amplifiers directly, without intermediate coupling elements. It is assumed that the zero volt dc output level should be relatively insenitive to both temperature and processing.

The final requirenent of Table II.l is to achicve the maximum - 3 dB bandwidth, without bandedge peaking, for a given quicscent power dissipation. Satisfaction of this small-signal criterion is the principal objective of the automated optimization procedure.

## TABLE II. 1

## DESIGN REQUIREMENTS

## 1. Moderate Voltage Gain (34dB)

2. High input and low output impedance levels
3. Low gain sensitivity
4. Standard IC processing
5. Dc-coupled with zero volt output level
6. Maximum -3 dB bandwidth

### 2.3 Commercial Amplifiers

A brief description of a number of commercially available integrated amplifiers provides a suitable introduction to basic approaches for meeting the requirements of Table II.l. These amplificrs more-or-less satisfy all of the requirements except that for de level shifting. All but one of the circuits are based on a fecdback approach.

The RCA CA3040 [1] is a differential cascode amplifier with emitter-follower stages at both input and output. The output emitter-follower is needed to meet the low output impedance requirement of Table II.1. The input emitterfollower is used to achieve a high input impedance and to buffer the input stage from the source. The inductive output of this emitter-follower also provides some shunt peaking at the input of the cascode. The performance of the the CA3040 configuration is described in Sec. 2.5.1.

The Fairchild $\mu \mathrm{A} 733$ [2] is a differential amplifier based on a seriesshunt local feedback cascade, with an output emitter-follower included in the shunt feedback stage. The basic amplifier configuration is shown in Fig. 2.1 (c). As brought out in Sec. 2.4, inclusion of the emitter-follower within the shunt feedback loop eliminates the loading of the feedback resistor at the output of the shunt feedback stage, thereby increasing the loop gain. A high input impedance is achieved in the $\mu A 733$ through the use of series feedback in the input stage.

Two commercial monolithic broadband amplifiers, the Sylvania SA-20 [3] and the SLGIlC [4] from Plessey Microelectronics of England, are based a series-shumt overall feedback pair. As for the $\mu A 733$, the output emitterfollower is included within the feedback loop. The basic configuration is illustrated in Fig. 2.1(a). Both of the commercial amplifiers are singleended, rather than differential, circuits.

The Motorola MC1553 [5] is a single-ended broadband amplifier based on a series-series feedback triple driving an output emitter-follower, as shown in Fig. 2.1(e). The design of the MC1553 has been described in detail by Solomon and Wilson [6]. This work is representative of the limits of complexity to which nonautomated broadband amplifier design can be extended.

### 2.4 A Feedback Approach

As is evident from the above description of commercial monolithic amplifiers, a feedback approach is commonly used to meet requirements similar to those given in Table II.1. Other approaches are possible but, as brought out in Sec. 2.5, these generally fail to satisfy one or more of the requirements.

Eight basic fecdback configurations suitable for meeting the requirements of Table II.1 are shown on Fig. 2.1. These configurations are arrived at through consideration of the possible applications of single-loop negative feedback in a cascade of two or three common-emitter gain stages with an output emitter-follower. * At most three gain stages have been considered because this is generally the largest number that can be effectively employed within an overall feedback loop.

In the arriving at the configurations of Fig. 2.1, only series feedback is allowed for the input stage because of the high input impedance requirement. In the cases where two or more feedback loops are cascaded, consideration is restricted to configurations with low interaction between the cascaded loops. For example, the series-shunt pair formed by the first and

[^0]
(a)

(b)

(c)

(d)

(g)

(h)

Fig. 2.1: Basic feedback configurations for voltage amplification.
second stages in Fig. $2.1(\mathrm{~g})$ must be folowed by a series feedback stage. If a shunt feedback stage were used instead, its low input impedance would severely load, and degrade the performance of, the preceding pair.

An output emitter-follower is included in the configurations of Fig. 2.1, because it is needed in all of the complete amplifier designs developed in Chapter $V$ as a buffer stage and as a means of establishing a low output impedance for the basic amplifier. In all but two of the circuits in Fig. 2.1, the emitter-follower is simply cascaded with a basic feedback configuration. However, in Fig. 2.1 (a) and (c) it has been included within a feedback loop. This inclusion climinates the loading of the feedback network at the output of the basic amplifier, thereby significantly increasing the loop gain of these configurations relative to the corresponding circuits in Fig. 2.1 (b) and (d). As indicated by the results presented in Chapter VI, the increase in loop gain leads to a significant improvement in the optimum performance achievable.

The configurations of Fig. 2.1 represent the basis for the complete amplifier designs developed in Chapter V. A balanced amplifier approach is employed and each of the designs is optimized for a specified gain and power dissipation. The optimization results are presented in Chapter VI and are used to establish the relative effectiveness of the basic configurations for broadband voltage amplification in integrated circuits.

### 2.5 Alternative Approaches

The feedback approach is not, in general, a necessary one for broadband amplification. Two notable monolithic exceptions to this approach are the RCA CA3040, introduced in Sec. 2.3, and a circuit developed by Gilbert [7]. Both of these amplifiers offer good broadband performance
under certain conditions but are not suitable for meeting all of the requirements of Table II.l.

### 2.5.1 The CA3040

The basic configuration of the $\mathrm{C} \Lambda 3040$ is shown in Fig. 2.2, along with the corresponding ac differential-mode half circuit [8]. The low-frequency voltage gain for this amplifier is given approximately by

$$
\begin{equation*}
A_{v}=\frac{q}{k T}\left(\frac{I_{1}}{2}\right) R_{1} \tag{2.1}
\end{equation*}
$$

where, as indicated in Fig. 2.2, $I_{1}$ is the quiescent current supplied to the differential cascode and $R_{1}\left(=R_{1}^{\prime}\right)$ is the differential load resistance for the cascode. In (2.1), $T$ is the absolute temperature in ${ }^{\circ} \mathrm{K}, \mathrm{q}$ is the magnitude of the charge on an electron, and $k$ is Boltzman's constant. To achieve a low gain sensitivity to temperature, the temperature dependence of the source current, $I_{1}$, must cancel the sensitivities of $R_{1}$ and $q / k T$. If this is the case, however, the quiescent voltage level at the output of the cascode is relatively sensitive to temperature. This de level may be approximately expressed as

$$
\begin{equation*}
\mathrm{V}_{\mathrm{C} 2} \simeq \mathrm{~V}_{\mathrm{CC}}-\frac{1}{2} \mathrm{I}_{1} \mathrm{R}_{1} \tag{2.2}
\end{equation*}
$$

where $V_{C C}$ is the positive supply voltage. For a low gain sensitivity, it is necessary to have $I_{1} R_{1} \propto T$. The corresponding condition in (2.2) is a linear dependence on $T$. As a numerical exanple, typical design values might be $V_{C C}=6 \mathrm{~V}$ and $\mathrm{V}_{\mathrm{C} 2}=3 \mathrm{~V}$ at a nominal temperature of $300^{\circ} \mathrm{K}$. For these values, under the condition $I_{1} R_{1} \propto T$, the dependence of $V_{C 2}$ on temperature


Fig. 2.2: (a) Basic configuration of RCA CA3040 wideband amplifier. (b) Ac differential-mode half circuit.


Fig. 2.3: Cascode circuit with series feedback.
is

$$
\begin{equation*}
v_{\mathrm{C} 2}=6-\left(\frac{\mathrm{T}}{100^{\circ} \mathrm{K}}\right) \mathrm{v} \tag{2.3}
\end{equation*}
$$

Over the temperature range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$, the total variation in $\mathrm{V}_{\mathrm{C} 2}$ is 1.8 volts, $60 \%$ of the nominal value.

To establish a low temperature sensitivity for $V_{C 2}$, the term $I_{1} R_{1}$ in (2.2) must be temperature insensitive. Therefore, the temperature dependence of the current source must be adjusted to cancel that of the diffused resistor, and some other means must be found to reduce the gain sensitivity. One obvious approach is to introduce a series feedback resistor into the cascode, as shown in Fig. 2.3. The low-frequency gain and sensitivity performance of this configuration is essentially the same as that for a single common-emitter stage with local series feedback. As such, the performance is insufficient for meeting the requirements of Table II.1.

### 2.5.2 The Gilbert "gain cell"

The amplifier shown in Fig. 2.4 is a wideband "gain cell" first described by Gilbert [9]. This circuit is a significant departure from conventional amplifier configurations and can be used to achieve stable gain with a large bandwidth and low distortion. Essentially, a common-base differential stage is connected in shunt with a common-emitter pair; the collector outputs for each pair are connected so that the output signals add in phase. Feedback is not used and the response of the configuration depends primarily on the ratio of the dc biasing currents, $I_{1}$ and $I_{2}$, and the matching between the active devices. The current gain is given by


Fig. 2.4: Gilbert gain cell.

$$
\begin{equation*}
A_{I}=\frac{i_{o u t}}{i_{\text {in }}}=1+\frac{I_{2}}{I_{1}} \tag{2.4}
\end{equation*}
$$

if ideal matching is assumed.
The Gilbert circuit is not suitable for meeting the requirements of Table II. 1 because, to achieve good performance, it must be loaded by a low impedance. This condition is not compatible with the emitter-follower output stage needed to provide a low output impedance. If a high load impedance is used, the Miller effect capacitance [10] is increased at the input of the common-emitter pair and, in a similar manner, the inductive effect at the input of the common-base devices is increased [11], [12]. As a result, the amplifier bandwidth is reduced and, if the load impedance is high enough, the increased LC product at the input of the gain cell may lead to severe response peaking.

## CHAPTER III

## AN AUTOMATED DESIGN PROGRAM

### 3.1 Introduction

In previous work [13], computer-aided analysis has been used extensively in the design of integrated broadband amplifiers. This work was carried out with programs that were currently available for small-signal circuit analysis in the complex frequency domain [14-16]. A number of feedback configurations were considered and the design results provide significant insight into the operation of these amplifiers. However, design optimization could be achieved only in a very limited form, such as the adjustment of compensation elements to provide maximum bandwidth. Convenient, but fixed, choices were made for transistor geometry, dc biasing, and many passive elements. Consequently, a definitive comparison of the basic feedback configurations could not be made. Such a comparison is feasible only if, for a given set of overall design specifications, the best performance obtainable can be established for each configuration under consideration. That is, each of the configurations must be optimized with respect to most, if not all, of the available degrees of design freedom.

In this chapter, a program that has been implemented to optimize the design of monolithic amplifiers is described. The program; ADOP, adjusts transistor geometry, dc operating conditions, and all passive elements to achieve an optimum small-signal amplifier response. Included in the circuit modeling for the program is the nonlinear dependence of the small-signal response on both de conditions and device geometry. In this dissertation,
the program is used to determine the maximum $-3 d B$ bandwidth obtainable for amplifier without peaking; however, the program may be used for optimization with respect to any design criteria that can be related to the small-signal response of a circuit.

The essential requirements for automated circuit design are a scalar performance index, efficient automated circuit analysis, efficient evaluation of the performance index gradient, and an optimization algorithm. In the following sections, each of the requirements is described in detail in relation to the design of monolithic broadband amplifiers. An outline of the program ADOP is presented in Appendix F, a complete listing of the program is given in Appendix G.

### 3.2 Performance Index

The basic procedure of automated circuit design is an iterative numerical search for the minimum of a scalar performance index. This index is a multivariable function of the design parameters and is formulated such that its minimum corresponds to an optimum design. A least squared error criterion has been used as a performance index for achieving a specified gain and maximum small-signal bandwidth:

$$
\begin{equation*}
E=\sum_{i=1}^{m} w\left(\omega_{i}\right)\left[\left|A_{v}\left(\omega_{i}\right)\right|-A\right]^{2} \tag{3.1}
\end{equation*}
$$

where $\omega_{i}, i=1, \ldots, m$ is a set of specified frequency points, $\left|A_{v}\left(\omega_{i}\right)\right|$ is the magnitude of the small-signal voltage gain at $\omega_{i}$, $A$ is the specified lowfrequency voltage gain, and $W\left(\omega_{i}\right), i=1, \ldots, m$ is a set of arbitrary, nonnegative, scalar weighting parameters. The weighting parameters are included in (3.1) to permit the selective emphasis of various segments of
the amplifier frequency response. For example, to ensure an adequately close realization of the specified gain at dc, the point $\omega_{i}=0$ may be given a larger weighting than points near the response bandedge.

The points $\omega_{i}$ define the frequency range over which the response error is evaluated. The choice of this range is critical if the minimum of the performance index (3.1) is to correspond to the maximum -3 dB bandwidth obtainable without peaking. If frequency points are selected too far beyond the amplifier bandedge, the optimization procedure may lead to a heavily peaked response in order to reduce the error beyond the bandedge. Conversely, if the frequency points are limited to a range well below the bandedge, the performance index is relatively insensitive to the response shape at the bandedge and the convergence properties of the iterative optimization procedure may be impaired. The choice of the frequency points, $\omega_{i}$, thus requires an approximate knowledge of the amplifier response. This can often be established from a preliminary analysis of the initial design choice in the optimization procedure; at worst, the frequency points can be rechosen after several design iterations.

### 3.3 Analysis

The performance index (3.1) is related directly to the gain-frequency response, $A_{v}(\omega)$. This response is evaluated at each frequency point, $\omega_{i}$, through analysis of an appropriate linear, small-signal circuit model. The nonlinear dependence of the response on dc conditions and transitor geometry is incorporated in the elements of the circuit model. A nodal admittance matrix formulation is used for the analysis, and the admittance equations are solved by means of an LU factorization [17-18]. The nodal admittance matrix, $Y$, is factored into a product of lower and upper triangular matrices, $L$ and $U$, using a straight forward Gaussian elimination procedure.

Because of the iterative nature of the automated design procedure, many analyses are needed to arrive at an optimum design. Consequently, the principal factor governing the overall cost of the procedure is the efficiency of the analysis routine. For the designs considered in this work, the typical CPI time required for evaluation of a performance index (3.1) with $m=10$ is 0.2 seconds on a CDC 6400. Sparse matrix techniques have not yet been implemented for solving the admittance equations, but preliminary considerations indicate that such an implementation may result in as much as an order of magnitude reduction in the analysis time.

### 3.4 Gradient Evaluation

The most effective algorithms for finding the minimum of a multivariable objective function by direct numerical search generally rely on repeated evaluation of both the function and its gradient. The classical technique for evaluation of the gradient is based on perturbations. Each of the variables is perturbed individually and the corresponding change in the objective function is determined. This information is then used to establish an approximation to the gradient.

For application to practical automated circuit design, the perturbation approach has two serious disadvantages. First, for n design variables, n additional analyses are needed for each trial design to determine the performance index gradient. These additional analyses represent an unacceptable increase in computational effort. The second limitation associated with the perturbation approach is the approximate nature of the gradient information. This information is accumulated in the optimization algorithm, and the possible crror build-up may seriously degrade the convergence properties of the algorithm.

An approach based on the formulation of the adjoint relations to a set of network equations overcomes both of the disadvantages associated with the perturbation approach [19,20]. Director and Rohrer have identified these adjoint relations in terms of the so-called linear adjoint network [21-23]. The adjoint network is topologically equivalent to the original circuit under consideration; there is a one-to-one correspondence between branches in the two networks. Under appropriate exitation of the adjoint network, the sensitivity of the performance index (3.1) to any element in a circuit may be expressed as a product of branch responses in the circuit and its adjoint network. Since the design variables are necessarily related to one or more of the circuit elements, evaluation of the performance index sensitivities to these elements leads directly to the gradient of the index with respect to the design variables. The derivation of the adjoint network and its properties is outlined in Appendix A for a restricted case; the derivation for the general case is described thoroughly in the references [21-23].

The adjoint network is an essential concept for practical circuit design automation. Through its use, the additional computational effort required for evaluation of the performance index gradient becomes less than that needed for evaluation of the index itself. It can be shown that the nodal admittance matrix for the adjoint network is simply the transpose of the nodal admittance matrix for the original circuit [24].. Hence, computations performed in decomposing the admittance matrix into an LU form need not be repeated. If

$$
\begin{equation*}
Y=L U \tag{3.2}
\end{equation*}
$$

then

$$
\begin{equation*}
\hat{Y}=Y^{t}=U^{t} L^{t} \tag{3.3}
\end{equation*}
$$

where $Y$ is the nodal admittance matrix of the original circuit and $\hat{Y}$ is the admittance matrix of the adjoint network.

The adjoint network approach, in addition to being extremely efficient, also has the advantage of providing a theoretically exact evaluation of the performance index gradient. The precision of the gradient is limited only by the computational machine accuracy.

### 3.5 Optimization

The direct numerical search for a minimum of a performance function generally consists of repeating a specified sequence of operations for a number of iterations until convergence to the minimum is obtained. The first step at each iteration is to choose a direction for continuing the search. A one-dimensional search is then conducted to locate a minimum of the function in this direction. The directional minimum is taken as the starting point for the next iteration. The procedure has converged when the directional minimum corresponds to a true minimum of the performance function.

When the gradient of the performance function is known, the classical search direction is that of steepest descent (the negative of the gradient direction). However, the steepest descent method exhibits limited convergence ability if the search encounters a narrow valley in n-dimensional surface of the performance function [25]. A number of algorithms have been developed to overcome this limitation; among the most powerful is the method of Fletcher and Powell [26-29]. In the Fletcher-Powell algorithm, the search direction is chosen on the basis of the gradient and an
approximation to the inverse of the matrix of second order derivatives in a Taylor Series expansion of the performance function. The approximation is established from the gradient information of preceding iterations; though necessarily poor at the beginning of the search, it continues to improve as the search proceeds. For the initial iteration, the direction of steepest descent is used. The method of Fletcher and Powell has been used with considerable success in the program ADOP. A brief description of the basis for the method is given in Appendix B.

Once a search direction has been chosen, steps are taken along it until a directional minimum is bounded. A cubic interpolation is then used to locate an approximate minimum. This method was suggested by Fletcher and Powell [30] and has proven satisfactory. No additional effort to locate the directional minimum more accurately appears to be warranted.

## CHAPTER IV

MODELING

### 4.1 Introduction

The precision and effectiveness of any theoretical circuit design procedure depends, in large part, on the models used for the circuit components. The principal benefit of using computer-aided analysis in a design procedure is the capability to deal efficiently with more complex circuit models than could otherwise be considered. In a procedure based on nonautomated circuit analysis, the highly approximate nature of the models that must be used for circuits of a practical complexity limits the precision of theoretical design work and results in the need for extensive experimental work.

Introduced in this chapter are the device structures and models used in the program ADOP for the design optimization of integrated broadband amplifiers. The vertical component geometry is defined by the assumption of a specific diffusion processing schedule. The general form of the planar transistor geometry is described and the design variables associated with this geometry are identified. A small-signal transistor model is then presented and the elements of the model are characterized on the basis of dc conditions, planar geometry, and the assumed processing schedule. Finally, the modeling of the significant parasitic elements associated with passive components is considered.

### 4.2 Device Structure

In this study, a specific bipolar integrated circuit processing schedule is assumed. The schedule is one of those commonly used in the integrated circuits processing facility at the University of California, Berkeley; it results in final base diffusion depth of $3.5 \mu \mathrm{~m}$, a base diffusion sheet resistance of $125 \Omega /$ square, and a basewidth of $0.8 \mu \mathrm{~m}$. An epitaxial resistivity of $1 \Omega-\mathrm{cm}$ is used. The diffusion depths for this particular processing schedule are somewhat large for high frequency performance and the low base sheet resistance results in a relatively high emitter-base junction transition capacitance. However, the low base sheet resistance is an asset for realizing relatively small resistances in a feedback network and, more importantly, consistently reproducible results have been obtained for the schedule.

The restriction to a particular processing schedule represents the only major arbitrary choice in the design procedure presented in this dissertation. Virtually all other significant degrees of freedom are incorporated actively into the design optimization procedure. The diffusion processing, and consequently the vertical component geometry, has not been included in the procedure because it is presently neither characterized nor controlled well enough to be represented by a set of continuously adjustable design parameters.

The general form assumed for the planar transistor geometry is illustrated by mask geometries shown in Fig. 4.1. The figures are drawn to scale and the minimum allowed values are used for all mask dimensions except the emitter stripe length in Fig. 4.1 (b). These minimum dimensions are well within present industrial capabilities.

(a)

(b)

## DIMENSIONS <br> IN MILS

Fig. 4.1: (a) Minimum area planar device geometry--n $=1, n_{b}=1$ and minimum emitter stripe length, $\ell=.6{ }^{e}$ mil.
(b) Device structure with $n_{e}=1, n_{b}=2$ and nonminimum $\ell_{e}$.

The device geometry design parameters are the emitter stripe length, $\ell_{e}$, the number of emitter stripes, $n_{e}$, and the number of base contact stripes, $n_{b}=\left(n_{e}+1\right)$ or $n_{e}$. Thesc variables govern the dependence of the ohmic resistances $r_{b}^{\prime}$ and $r_{c}^{\prime}$ and junction transition capacitances on the planar geometry; this dependence reflects the principal effect of geometry on the frequency response in the amplifier configurations to be considered. Minimum values are used for all planar dimensions except the emitter stripe length.

The structure shown in Fig. 4.1(a) represents the minimum size device allowed; it has a single base contact and the minimum emitter stripe length, $\ell_{e}=0.6 \mathrm{mil}$, resulting in a square emitter. Fig. 4.1 (b) is an example of a device with $n_{e}=1, n_{b}=2$, and a nonminimum emitter stripe length.

An $\mathrm{n}^{+}$buried layer structure is assumed for all devices. The buried layer is located under the region encompassed by the $n^{+}$collector contact ring and the base diffusion. The collector contact window may be positioned anywhere along the 0.2 mil wide $\mathrm{n}^{+}$ring without significantly affecting the device characteristics.

### 4.3 A Small-Signal Transistor Model

The small-signal transistor circuit model used in this work is shown in Fig. 4.2. The model is basically a hybrid- $\pi$ configuration [31-33] with RC $\pi$-sections used to represent the distributed base and collector structures. It represents a compromise between precise representation of device performance and modeling complexity. For device design work [34], a far more complicated distributed model [35] may be appropriate; however, such models are hopelessly inefficient for the repeated circuit analyses needed in an automated circuit design procedure. Conversely, the model of Fig. 4.2 is

- a

Fig. 4.2: Small-signal transistor model.
too complex for many nonautomated design problems. If carefully characterized, the model of Fig. 2.4 provides a good representation of small-signal device performance up to frequencies on the order of the common-emitter unity current gain frequency, $f_{T}$ [36].

The design variables that are associated with the transistor biasing conditions and planar geometry are brought into the design optimization procedure through the elements of the small-signal device model. The characterization of the model elements for the assumed diffusion processing is described below; this characterization is based both on experimental data and first-order geometrical considerations. In the experimental processing facility presently available at Berkeley; the minimum mask dimensions are somewhat larger than those indicated in Fig. 4.1; for example, the smallest emitter stripe width (and length) is 1.6 mil rather than 0.6 mil . As a result, experimental data has, in some cases, been extrapolated to the smaller dimension devices. The resulting characterization is typical of devices that can be realized easily in most commercial processing facilities.

A summary of the device characterization results is presented in Table IV.1. The basis for the characterization is empirical, and a number of the relationships in the table represent the best fit to experimental data. The relationships are not necessarily meaningful from either a physical or theoretical standpoint. In any given design situation, the characterization should be carried out on the basis of the actual processing facility to be used.

Transconductance, $\delta_{m}$ : The small-signal transconductance of a bipolar transistor is given directly by the well known relationship

$$
\begin{equation*}
g_{m}=\frac{q}{k T} I_{C} \tag{4.1}
\end{equation*}
$$

## TABLE IV. 1

DEVICE CHARACTERIZATION

$$
\begin{aligned}
& g_{m}=\frac{q}{k T} I_{C} \\
& r_{\pi}=\beta_{0} / g_{m}, \quad \beta_{0}=120 \\
& r_{0}=1 / n g_{m}, \quad \tau_{t}=.22 \mathrm{~ns} \\
& C_{\pi}=C_{j e}+g_{m} \tau_{t}, .00065 \\
& C_{j e} / \text { Area }=1.25 \mathrm{pF} / \mathrm{mil}^{2} \\
& C_{c b} / \text { Area }=\frac{.11}{\left(\psi_{c}-V_{B C}\right)^{k_{c}}} \mathrm{pF} / \mathrm{mil}^{2} \\
& C_{c s} / \text { Area }=\frac{.044}{\left(\psi_{s}-V_{S C}\right)^{k_{s}}} \mathrm{pF} / \mathrm{mil}^{2}
\end{aligned}
$$

where

$$
\begin{gathered}
\psi_{b}=.4 V \\
\psi_{c}=.4 V \quad k_{b}=.275 \\
r_{b}^{\prime}=\frac{1}{n_{b}}\left[210+\frac{200}{\left(I_{c}+1.3\right)}\right]\left(\frac{1}{.525 \ell_{e}+.15}\right) \Omega \\
r_{c}^{\prime}=30\left[\frac{3.5}{\left(2.3+.9 n_{e}+.5 n_{b}+\ell_{e}\right)}+\frac{.2}{n_{e}}\right] \Omega
\end{gathered}
$$

where $I_{C}$ is in $m A$ and $\ell_{e}$ is in mils.
where $I_{C}$ is the quiescent collector current. This parameter is independent of device geometry.

Input resistance, $r_{\pi}$ : The small-signal resistance, $r_{\pi}$, models the effects which contribute to a nonzero base current in a bipolar transistor. This resistance is given by

$$
\begin{equation*}
r_{\pi}=\beta_{0} / g_{m} \tag{4.2}
\end{equation*}
$$

where $\beta_{0}$ is the incremental, low-frequency, common-emitter current gain of the device. In the designs to be described, the constant value

$$
\begin{equation*}
\beta_{0}=120 \tag{4.3}
\end{equation*}
$$

has been assumed.
The current gain, $\beta_{0}$, is nominally a function of both biasing and geometry. However, this parameter is governed by recombination mechanisms that are not well characterized and, over the ranges of interest in this study, the dependence on current level and geometry is masked by run-to-run and slice-to-slice variations. In addition, for the amplifiers considered, the response is relatively insensitive to $\beta_{0}$; this is a necessary condition for any bipolar integrated circuit design that is to be insensitive to temperature and processing.

Output resistance, $r_{0}$ : The small-signal output resistance, $r_{0}$, models the effect of basewidth modulation $[37,38]$ and may be expressed as

$$
\begin{equation*}
r_{0}=\frac{1}{n g_{\mathrm{m}}} \tag{4.4}
\end{equation*}
$$

where $\eta$ is the basewidth modulation factor. A typical value measured for $r_{0}$ at a collector current of $I_{C}=1 \mathrm{~mA}$ is $40 \mathrm{k} \Omega$. This corresponds to a basewidth
modulation factor of

$$
\begin{equation*}
\eta=.00065 \tag{4.5}
\end{equation*}
$$

Base resistance, $r_{b}^{\prime}$ : The principle influence of the ohmic base resistance, $r_{b}^{\prime}$, in a configuration such as those of Fig. 2.1 is with respect to the bandedge response. For this reason, $r_{b}^{\prime}$ has been evaluated experimentally for a number of devices using the method of high-frequency input impedance measurements [39]; this method leads to values of $r_{b}^{\prime}$ appropriate to the bandedge performance. The method has also been found to yield results that closely agree with noise measurements of $r_{b}^{\prime}$ [40]. A brief description of the method and some typical results are given in Appendix C.

The base resistance is strongly dependent on both geometry and dc current level. Typical measured values for $r_{b}^{\prime}$ as a function quiescent collector current is given in Fig. 4.3 for a minimum area, single base contact device. As indicated in the figure, the dependence of base resistance on current is modeled well by the relationship

$$
\begin{equation*}
\left.r_{b}^{\prime}\right|_{\min }=\left[210 \Omega+\frac{200}{\left(I_{C}+1.3\right)}\right] \Omega \tag{4.6}
\end{equation*}
$$

where $I_{C}$ is in $m A$.
As noted previously, limitations in the available processing system have restricted the minimum planar dimensions for experimental devices to values somewhat larger than those indicated in Fig. 4.1. Consequently, the data of Fig. 4.3 corresponds to a device that has the same form as Fig. 4.1(a) but is scaled upward in size. Nominally, in the presence of dc crowding, such a scaling alters the base resistance, $r_{b}^{\prime}$. However, because of

counteracting effects associated with the dimensional scaling, it is reasonable to assume that $r_{b}^{\prime}$ is not changed substantially. For a given dc current level, an increase in emitter area reduces the dc crowding and tends to increase $r_{b}^{\prime}$. At the same time, however, the increase in the emitter stripe length tends to reduce $r_{b}^{\prime}$ as long as a significant component of the resistance is associated with the active base region under the emitter. The relatively large magnitudes measured for $r_{b}^{\prime}$ indicate that this latter condition is certainly satisfied for the case of Fig. 4.3, even in the region of heavy dc crowding. Thus, the expression (4.6) is assumed to be typical for devices with the dimensions shown in Fig. 4.1(a), as well as for the actual experimental devices. In another design situation, measurements of the effects of dc crowding on $r_{b}^{\prime}$ should be made corresponding to the actual processing schedule and mask dimensions to be used.

The expression (4.6) is the characterization assumed for the base resistance of the minimum area device in Fig. 4.1(a). The characterization of $r_{b}^{\prime}$ for the general device form is obtained by including the dependence on planar geometry, resulting in

$$
\begin{equation*}
\mathrm{r}_{\mathrm{b}}^{\prime}=\frac{1}{\mathrm{n}_{\mathrm{b}}}\left[210+\frac{200}{\left(\mathrm{I}_{\mathrm{C}}+1.3\right)}\right]\left(\frac{1}{1.42 \ell e^{+.15}}\right) \Omega \tag{4.7}
\end{equation*}
$$

where $\ell_{e}$ is the emitter stripe length in mils, $I_{C}$ is the collector current in $m A$, and $n_{b}$ is the number of base stripes. The geometrical dependence in (4.7) is arrived at through simple first-order estimates based on the mask dimensions given in Fig. 4.1.

Collector resistance, $r_{c}^{\prime}$ : For planar geometries such as shown in Fig. 4.1, with an $n^{+}$buried layer structure, the principal component of $r_{c}^{\prime}$ is the vertical resistance between the $\mathrm{n}^{+}$collector ring and the buried layer.

In this situation, an appropriate representation of the collector resistance as a function of geometry is

$$
\begin{equation*}
r_{c}^{\prime}=30\left[\frac{3.5}{2.3+.9 n_{e}+.5 n_{b}+l}+\frac{-2}{n_{e}}\right] \Omega \tag{4.8}
\end{equation*}
$$

where $\ell_{e}$ is in mils. This relationship corresponds to a resistance of $30 \Omega$ for the minimum area geometry of Fig. 4.1(a). The dependence on geometry is relatively weak and for most of the devices to be considered, $r_{c}^{\prime}$ is in the range of $25 \Omega$ to $30 \Omega$.

Base-emitter Capacitance, $\mathrm{C}_{\pi}$ : The base-emitter capacitance, $\mathrm{C}_{\pi}$, represents two components of charge storage and may be expressed as

$$
\begin{equation*}
C_{\pi}=C_{j e}+g_{m} \tau_{t} \tag{4.9}
\end{equation*}
$$

The first term in this expression, $\mathrm{C}_{\mathrm{je}}$, is the transition capacitance of the emitter-base junction. The second term models the storage of injected minority carriers in the base. $\tau_{t}$ is the transit time of the injected carriers and includes the transit time for both the intrinsic base region and the collector depletion region [41].

For the current levels of interest in this work, the increase in $\tau_{t}$ at high currents $[41,42]$ may be neglected and a constant value assumed.

A typical value of $\tau_{t}$ for the specified diffusion processing is

$$
\begin{equation*}
\tau_{t}=.22 \mathrm{nsec} \tag{4.10}
\end{equation*}
$$

This value was determined from measurements of $f_{T}$ as a function of collector current in the range below that where $\tau_{t}$ begins to increase.

A plot of the emitter-base transition capacitance per unit area as a
function of voltage, for the specified diffusion schedule, is given in Fig. 4.4. Based on this data, a value of $1.25 \mathrm{pF} / \mathrm{mil}^{2}$ is assumed for all devices in the circuits to be considered. The capacitance per unit area together with the emitter-base junction area is used to determine $C_{j e}$. The junction area is given by

$$
\begin{equation*}
A_{e}=n_{e}\left(.93 \ell_{e}+.27\right) \operatorname{mil}^{2} \tag{4.11}
\end{equation*}
$$

where $\ell_{e}$ is in mils. In establishing (4.11), both lateral diffusion and sidewall area are considered.

Base-collector Capacitance, $\mathrm{C}_{\mathrm{cb} 1}$ and $\mathrm{C}_{\mathrm{cb} 2}$ : The collector-base capacitance may be regarded entirely as the transition capacitance of the collector-base junction. The basewidth modulation component generally associated with the collector-base capacitance $[44,45$ ], is given by

$$
\begin{equation*}
c_{\eta}=g_{m} \tau_{t} \eta \tag{4.12}
\end{equation*}
$$

For the values given above for $\eta$ (4.5) and $\tau_{t}$ (4.10), the value of $C_{\eta}$ at a collector current of 1 mA is . 0055 pF . This is completely negligible in comparison with the transition capacitance.

A plot of collector-base capacitance per unit area as a function of voltage for a typical device is given in Fig. 4.5. This data is well fit by the relationship

$$
\begin{equation*}
\mathrm{C}_{\mathrm{cb}} / \text { Area }=\frac{.11}{\left(\psi_{\mathrm{c}}-\mathrm{V}_{\mathrm{BC}}\right)^{\mathrm{k}_{\mathrm{c}}}} \mathrm{pF} / \mathrm{mil}^{2} \tag{4.13}
\end{equation*}
$$

where $\psi_{C}=.4$ volts, $k_{c}=.275$ and $V_{B C}$ is in volts. This expression represents a best fit to experimental data and is not meaningful in terms


of an ideal pn junction. The low value of built-in voltage, $\psi_{c}$, can be used because, for all devices considered, the collector-base junction is reverse biased $\left(V_{B C}<0\right)$.

The total collector-base capacitance has been modeled with two capacitors, $C_{c b 1}$ and $C_{c b 2}$, in order to represent the distributed nature of the device structure. The principal component of the base resistance, $r_{b}^{\prime}$, occurs in the active base region near the perimeter of the emitter diffusion window. For this reason, the collector-base capacitance is divided on the basis of the junction area associated with the active and passive base regions.

$$
\begin{align*}
& C_{c b 1}=\left(C_{c b} / \text { Area }\right)\left(A_{e}\right)  \tag{4.14}\\
& C_{c b 2}=\left(C_{c b} / \text { Area }\right)\left(A_{b}-A_{e}\right) \tag{4.15}
\end{align*}
$$

where $A_{e}$ is the emitter-base junction area, given by (4.11), and $A_{b}$ is the collector-base junction area, which is given by

$$
\begin{equation*}
A_{b}=\left(\ell_{e}+.82\right)\left(.9 n_{e}+.5 n_{b}+.52\right)-.078 \operatorname{mil}^{2} \tag{4.16}
\end{equation*}
$$

where $\ell_{e}$ is in mils.
Collector-substrate Capacitance, $\mathrm{C}_{\mathrm{cs} 1}$ and $\mathrm{C}_{\mathrm{cs} 2}$ : The parasitic collector-substrate transition capacitance is modeled in the same manner as collector-base junction, with two capacitances, $C_{c s 1}$ and $C_{c s 2}$. Since the major component of $r_{c}^{\prime}$ is the resistance between the $n^{+}$collector ring and the buried layer, $C_{c s l}$ is regarded as the capacitance associated with the collector region that is shaded in the device layout shown in Fig. 4.6. The junction area corresponding to this region is given by

$$
\begin{equation*}
A_{c s 1}=\left(\ell_{e}+2.3\right)\left(.9 n_{e}+.5 n_{b}+1.1\right) \operatorname{mil} 1^{2} \tag{4.17}
\end{equation*}
$$



AREA $A_{\text {csI }}$

Fig. 4.6: Collector area associated with $\mathrm{C}_{\mathrm{cs} 1}$.
where $\ell_{e}$ is in mils. The total collector-substrate junction area is given by

$$
\begin{equation*}
A_{c s}=\left(\ell_{e}+3.7\right)\left(.9 n_{e}+.5 n_{b}+3.9\right)-.64 \operatorname{mil}^{2} \tag{4.18}
\end{equation*}
$$

For both (4.17) and (4.18), lateral diffusion and sidewall area is considered.
A plot of measured values for the collector-substrate capacitance per unit area, corresponding to a typical device, is given in Fig. 4.7. The data is well fit by the expression

$$
\begin{equation*}
\mathrm{C}_{\mathrm{cs}} / \text { Area }=\frac{.044}{\left(\psi_{\mathrm{s}}-\mathrm{V}_{\mathrm{SC}}\right)^{\mathrm{k}_{\mathrm{s}}}} \mathrm{pF} / \mathrm{mil}^{2} \tag{4.19}
\end{equation*}
$$

where $\psi_{s}=.4$ volts and $k_{s}=.34$. As for the collector-base junction, the collector-substrate junction will always be reversed biased $\left(V_{S C}{ }^{<0}\right)$ in the designs considered here. The appropriate expressions for $C_{c s 1}$ and $C_{c s 2}$ are

$$
\begin{align*}
& C_{c s 1}=\left(C_{c s} / \text { Area }\right) \cdot A_{c s 1}  \tag{4.20}\\
& C_{c s 2}=\left(C_{c s} / \text { Area }\right)\left(A_{c s}-A_{c s 1}\right) \tag{4.21}
\end{align*}
$$

For most cases, the collector substrate junction will be heavily reverse biased in the range of 6 to 9 volts and can be reasonably modeled with a voltage independent capacitance per unit area of $.06 \mathrm{pF} / \mathrm{mil}^{2}$.

### 4.4 Passive Component Parasitics

For the designs considered in this study, the only significant parasitic elements related to passive components are the distributed capacitances associated with the diffused collector load resistors in each amplifier stage. Since one end of these resistors is connected to the


(a)

(b)

Fig. 4.8: Modeling of diffused collector load resistors.
(a) Distributed model.
(b) Single-pole approximation.
positive de supply, or a virtual ground node in a differential configuration, the resistors may be viewed as a resistive one-port, such as shown in Fig. 4.8 (a).

If, to a first-order approximation, a uniform capacitance per unit area is assumed, the distributed one-port can be modeled by the single pole network shown in Fig. 4.8 (b). In the figure, $C$ is the total capacitance associated with the resistor. This capacitance is given approximately by

$$
\begin{equation*}
C=\frac{R}{\rho_{0}} A_{\square} C_{A V} \tag{4.22}
\end{equation*}
$$

where $\rho_{a}$ is the sheet resistance of the base diffusion, $A_{a}$ is the junction area of a square of resistance, and $\mathrm{C}_{\mathrm{AV}}$ is the average capacitance per unit area. For the assumed processing schedule, $\rho_{\square}=125 \Omega /$ square, and $C_{A V}=.08 \mathrm{pF} / \mathrm{mil}^{2}$. A typical resistor line width for the collector load resistors is .3 mil ; for this case $A_{\square}=.27 \mathrm{mil}^{2}$ if sidewall area is considered.

## CHAPTER V

## COMPLETE AMPLIFIER DESIGNS

### 5.1 Introduction

The subject of this chapter is the development of complete amplifier designs based on the configurations first introduced in Fig. 2.1. A comnon overall design approach is used and is adapted individually to each of the basic feedback configurations. The designs are then optimized to provide the maximum -3 dB bandwidth consistent with specified gain, power supplies, and power dissipation. The results of the design optimization are presented in Chapter VI and are used to compare the configurations of Fig. 2.1.

The eight basic feedback configurations introduced in Chapter II are repeated in Fig. 5.1, and are identified by the notation P1 through P4 and T1 through T4. The configurations with two common-emitter stages ${ }^{*}$ are henceforth refered to as pairs and are denoted by P1 through P4. Those configurations with three gain stages are refered to as triples and are identified by the notation T1 through T4. For corresponding numbers, such as T1 and Pl, the connection of the feedback resistor $R_{f}$ is the same in both the pair and the triple. As indicated by Fig. 5.1, the difference between the corresponding pairs and triples is that the third stage in the pair is operated as an emitter follower, while in the triple it is used as a commonemitter gain stage.

See footnote in Sec. 2.3, pg. 8.


PL


P3



TI


TR


TB


TH

Fig. 5.1: Basic configurations with identifying notation, P1-P4 and T1-T4.

In all of the triples, Tl -T4, in Fig. 5.1, and in two of the pairs, P2 and P4, a basic feedback configuration is simply cascaded with the output emitter-follower. However, for the other two pairs, P1 and P3, the emitter-follower is included within a feedback loop. As indicated by the comparison of optimum designs presented in Sec. 6.4, the inclusion of the emitter-follower within a feedback loop results in a significant increase in the maximum achicvable bandwidth.

### 5.2 Overall Design Approach

The general design approach adopted for meeting the requirements of Table II. 1 is illustrated in Fig. 5.2. A basic amplifier configuration, enclosed within the dashed lines, is employed in a balanced, or differential, manner and is biased with common-mode current sources such as $I_{1}$ and $I_{2}$. The emitter-follower of the basic amplifier is incorporated in a dc level shifting stage and an output emitter-follower is added to establish a low output impedance.

A balanced amplifier approach has been used in order to achieve a dc-coupled response with zero volt input and output quiescent levels, temperature and processing insensitive biasing, and a differential inputoutput capability. As brought below, the common-mode current sources in Fig. 5.2 are realized in manner that establishes relatively insensitive dc voltage levels at the collectors in the basic amplifier configuration.

The balanced amplifier approach permits a partial separation of the dc and ac design problems. Once an optimum set of dc current levels is established from ac considerations, these currents can be easily realized without affecting the differential-mode response of the amplifier. This response is not directly influenced by the nature of the current source realization.

Fig. 5.2: General design approach.

As noted in Chapter II, dc level-shifting must be incorporated within the complete monolithic design. In the approach of Fig. 5.2, the dc voltage level is shifted across the resistor $R_{1}$. The level shifting network is isolated from the basic amplifier by the emitter-follower $Q_{L}$ and the dc current in the stages is supplied through the resistor $R_{2}$. Resistive biasing has been used, despite its associated attenuation, because previous work [46] has demonstrated that this is the only level shifting configuration, compatible with standard monolithic processing, that does not limit the overall amplifier bandwidth. For example, if $R_{2}$ is replaced with a transistor current source, the attenuation is eliminated but the frequency response is severely degraded by the output capacitance of the current source.

In the following sections, complete amplifier designs based on the configurations of Fig. 5.1 are presented. Designs for the series-series triple, T1, and the series-shunt pair, Pl, are first described in detail. The designs for the remaining configurations are then presented with emphasis of features differing from the first two descriptions. All of the designs are developed and optimized on the basis of the principal specifications that are summarized in Table V.l: 1) a differential voltage gain of $34 \mathrm{~dB}, 2) \pm 6 \mathrm{~V}$ power supplies, and 3) a quiescent power dissipation of 96 mV , corresponding to total dc current of 8 mA between the supplies.

### 5.3 Series-Series Triple, T1

### 5.3.1 de Considerations

Shown in Fig. 5.3 is a complete amplifier with the series-series triple, Tl, used as the basic amplifier configuration. Dc currents for the triple are supplied by the common-mode current source configuration of

## TABLE V.I

PRINCIPAL OVERALL DESIGN SPECIFICATIONS

1. Differential Voltage Gain $=34 \mathrm{~dB}$
2. $\pm 6 \mathrm{~V}$ Power Supplies
3. Power Disspiation $=96 \mathrm{~mW}$


Fig. 5.3: Complete amplifier design based on configuration T1.
$Q_{6}, Q_{7}$ and $R_{7}$. All of the quiescent current for the third stage of the triple, $Q_{3}$, is provided by the current source transistor $Q_{6}$ and is drained through the feedback resistor, $R_{f}$; as a result, this resistor is important from the standpoint of both biasing and gain. The distribution of current among the three stages of the triple is governed by $R_{f}, R_{7}$ and the ratio of currents in $Q_{6}$ and $Q_{7}$. As is demonstrated in Appendix $D$, this form of biasing leads to a de voltage at the collector of $Q_{3}$, the output of the triple, that is relatively insensitive to both processing and environment.

The dc collector-emitter voltages of the first two stages in the series-series triple are specified at 1.4 V . This specification is also adopted for the first two stages in the other triple (T2-T4) designs, as well as the first stage in all of the pair (P1-P4) designs. These voltages could be incorporated as independent variables in the design optimization procedure; however, little is gained by doing this because of the limited range over which the voltages may be adjusted. For values much below the 1.4 V specification, amplifier linearity may be impaired, while significantly larger values limit the available output voltage swing. The collector voltage for the third stage of the triple is determined after consideration of the level shifting and output stage design.

### 5.3.2 Level Shifting and Output Stages

The dc voltage level in the amplifier of Fig. 5.3 is shifted across the resistor $R_{4}$, with the emitter-follower $Q_{4}$ isolating the basic triple from the level shifting network. Dc current for the stage is supplied through the resistor $R_{5}$ and the common-mode diode string, $D_{1}-D_{5}$. The output emitterfollower, $Q_{5}$, provides the required low output impedance and also buffers the level shifting network from the load. Such buffering is needed if
the attenuation in the level shifting stage is to be relatively independent of the load.

The common-mode diode string is used in the level shifting stage to cancel the effects on the quiescent output voltage of changes in the base emitter voltages of $Q_{4}$ and $Q_{5}$ with temperature. The basis for this cancelation can be demonstrated through consideration of the generalized n -diode configuration shown in Fig. 5.4. In this figure, $\mathrm{V}_{\mathrm{C} 3}$ corresponds to the voltage at the collector of $Q_{3}$ in Fig. 5.3. If the transistors $Q_{4}$ and $Q_{5}$ and the diodes $D_{1}-D_{5}$ are fabricated such that $V_{B E}\left(Q_{4}\right)=V_{B E}\left(Q_{5}\right)=\phi$, then the dc output voltage may be expressed as

$$
\begin{equation*}
v_{0}=-v_{E E}+\left(v_{E E}+V_{C 3}\right) A_{L V}+\phi\left[n-1-(n+1) A_{L V}\right] \tag{5.1}
\end{equation*}
$$

where

$$
\begin{equation*}
A_{L V}=\frac{R_{5}}{R_{4}+R_{5}} \tag{5.2}
\end{equation*}
$$

is the small-signal differential voltage transmission of the level shifting stage. The dependence of $\mathrm{V}_{0}$ on the junction voltages in the level shifting and output stages can be eliminated by setting the coefficient of $\phi$ in (5.2) to zero, resulting in the requirement

$$
\begin{equation*}
A_{L V}=\frac{n-1}{n+1} \tag{5.3}
\end{equation*}
$$

Under the condition (5.3), the specified zero volt quiescent output level $\left(v_{0}=0\right)$ is obtained when

$$
\begin{equation*}
\mathrm{v}_{\mathrm{C} 3}=\mathrm{v}_{\mathrm{EE}}\left(\frac{1}{\mathrm{~A}_{\mathrm{LV}}}-1\right) \tag{5.4}
\end{equation*}
$$



Fig. 5.4: Generalized level shifting and output stage configuration.

A zero volt de output that is relatively insensitive to temperature and processing can be established through a consistent choice of $n$ and $V_{C 3}$ satisfying (5.3) and (5.4). The output voltage is, however, sensitive to the negative supply voltage, $V_{E E}$, and the output voltage of the basic amplifier, $V_{C 3}$. As indicated in Appendix $D$ the common-mode current source biasing used for the basic amplifier in Fig. 5.3 results in a voltage for $V_{C 3}$ that is relatively insensitive to temperature and processing.

Several factors must be considered in choosing $n, V_{C 3}$ and $A_{L V}$. First, $n$ is obviously restricted to integer values. Second, the voltage $V_{C 3}$ should correspond to a near-maximum available voltage swing at the output of the amplifier. Finally, the voltage transmission, $A_{L V}$, should be the maximum consistent with the first two considerations.

Values of $V_{C 3}$ and $A_{L V}$ for several choices of $n$ are given in Table V. 2 for $\pm 6 \mathrm{~V}$ supplies. For the amplifier of Fig. 5.3, $\mathrm{n}=5$ has been chosen. This corresponds to a $3 V$ dc level at the collector of $Q_{3}$ and a voltage transmission of .67 for the level shifting stage. The corresponding voltage swing available in the negative direction at the collector of $Q_{3}$ is approximately 2.3V, as determined from the 1.4 volt collector-emitter voltages of the first two stages and the assumption of a base-emitter voltage of .7 volts for $Q_{1}, Q_{2}$ and $Q_{3}$.

The values of the resistors $R_{4}, R_{5}$ and $R_{6}$ are determined from the dc current specifications for the level shifting and output stages. The values of the resistors $R_{4}$ and $R_{5}$ must be low enough so that the $R C$ time constant at the base of $Q_{5}$ does not limit the amplifier bandwidth, and the current in the output emitter-follower must be high enough to provide a reasonable output current capability. For the total specified power dissipation of

TABLE V. 2

LEVEL SHIFTING AND OUTPUT STAGE DESIGN
(Fig. 5.4) FOR $\pm 6$ VOLT SUPPLIES

| Number of <br> Diodes <br> $n$ | Quiescent Input <br> Voltage Level <br> $V_{\text {C3, volts }}$ | Differential <br> Voltage Transmission |
| :---: | :---: | :---: |
| 4 | 4.0 | $A_{\text {LV }}$ |
| 5 | 3.0 | .60 |
| 6 | 2.4 | .67 |
| 7 | 2.0 | .715 |

$96 \mathrm{~mW}, 48 \mathrm{~mW}$ is allotted to the level shifting and output stages. Current levels of 1 mA can then be specified for each of the transistors in these stages. The corresponding resistors values are $1.6 \mathrm{k} \Omega$ for $R_{5}$, and $6.0 \mathrm{k} \Omega$ for $R_{6}$. The net differential mode resistance from the base of $Q_{5}$ to ground is $1.07 \mathrm{k} \Omega$. Fór thesc values of resistance, computer-aided analysis has verified that the overall frequency response of any of the designs considered is not limited by the response of the level shifting and output stages.

### 5.3.3 Frequency Compensation

The level shifting stage, output emitter-follower and the common-mode elements of the amplifier of Fig. 5.3 do not directly affect the overall differential frequency response of the amplifier. Therefore, this response can be determined from analysis of the differential mode half-circuit [47] for the basic triple, shown in Fig. 5.5. Design variables that are not explicitly present as elements of the half-circuit are entered into the design optimization process either through the elements of the small-signal models or as constraints on the half-circuit components. The loading on the triple is represented in the circuit of Fig. 5.5 by the resistor $R_{3}$ and the capacitor $C_{L}^{\prime}$. The capacitor models both the input capacitance of the level shifting stage and the parasitic capacitance associated with $\mathrm{R}_{3}$. The input resistance of the level shifting network is much greater than $R_{3}$ and may be neglected.

A common approach to the frequency compensation of feedback configurations such as Fig. 5.5 is to introduce a zero into the feedback transmission (a phantom zero) with a shunt capacitor across the resistor $R_{f}$ [48]. In the series-series triple, however, compensation can instead be established with an effective feedback zero that is inherent in the configuration.


Fig. 5.5: Differential-mode half circuit for the basic triple in the amplifier of Fig. 5.3.

In any circuit with a series fecdback connection at the output, the feedback network samples the emitter current of the output transistor rather than the actual output signal ( $v_{0}$ in Fig. 4). This situation results in a zero of the feedback transmission that is given approximately by [49]

$$
\begin{equation*}
z_{0} \approx-\frac{1}{R_{3}\left(C_{c b}+C_{c s}+C_{L}^{1}\right)} \tag{5.5}
\end{equation*}
$$

where $C_{c b}$ and $C_{c s}$ are the collector-base and collector-substrate capacitances of the output transistor, $Q_{3}$.

Optimal compensation of the triple can be achieved through suitable choices for the resistor $R_{3}$ and the capacitor $C_{L}$. Introduction of a common-mode resistor, $R_{8}$ in Fig. 5.3, allows $R_{3}$ to be varied below an upper bound without disturbing the dc conditions. Small values of $R_{3}$ should, however, be avoided because they limit the available voltage swing at the output of the triple. If necessary, the capacitance $C_{L}^{\prime}$ can be increased by enlarging the area of the diffused resistor $R_{3}$; it should not be necessary to add separate capacitive elements for compensation.

### 5.3.4 Design Variables and Constraints

The variables in the design optimization procedure for the amplifier of Fig. 5.3 are the feedback resistors $R_{e 1}, R_{e 2}$, and $R_{f}$; the differential collector load resistors, $R_{1}, R_{2}$ and $R_{3}$, which can be varied independently of the dc conditions, below an upper bound, through the use of common-mode resistors such as $R_{8}$; the dc currents in the triple as governed by $R_{7}$ and the ratio of currents in $Q_{6}$ and $Q_{7}$; and the planar geometry variables, described in Chapter IV, for the devices $Q_{1}, Q_{2}$ and $Q_{3}$. Design constraints imposed on these variables are: 1) all passive elements must be nonnegative
2) the specified collector-emitter voltage of $1.4 V$ for $Q_{1}$ and $Q_{2}$, 3) the $3 V$ de level at the collector of $Q_{3}$, as determined by the output stage design, 4) the de voltage drop across the resistor $R_{f}$, through which the emitter current of $Q_{3}$ is drawn, 5) the upper bound on the differential collector load resistors imposed by dc conditions, 6) a total quiescent current of 2 mA for each side of the balanced triple, resulting from the specifications of Table V. 1 and the 48 mW dissipation in the level shifting and output stages, and 7) a minimum emitter stripe length of 0.6 mil for the devices $Q_{1}, Q_{2}$ and $Q_{3}$.

### 5.4 Series-Shunt Pair, P1

A complete amplifier based on the series-shunt pair, P1, is shown in Fig. 5.6. The biasing approach is the same as that used in the amplifier of Fig. 5.3; the common-mode current source supplies the currents for the basic pair and the current drain throug $R_{f}$. As shown in Appendix $E$, this configuration results in a relatively insensitive quiescent voltage level at the collector of $Q_{2}$. Therefore, the same general level shifting and output stage configuration as used for the amplifier of Fig. 5.3 can be employed to achieve an insensitive, zero volt quiescent output level.

The collector-emitter voltage in the first stage of the pair, $Q_{1}$, is specified at 1.4 V , and the available output voltage swing is determined by voltage at the collector of $Q_{2}$. This voltage may be less than the collector voltage of $Q_{3}$ in the triple, while a comparable output swing is achieved, because the voltage at the cmitter of $Q_{2}$ in Fig. 5.6 is less than that at the emitter of $Q_{3}$ in Fig. 5.3. Therefore, a six-diode string has been used for the level shifting network in Fig. 5.6. From the data in Table V.2, for $n=6, V_{C 2}=2.4$ volts and $A_{L V}=.715$. The use of six diodes increases the


Fig. 5.6: Complete amplifier design based on configuration P1.
voltage transmission and also reduces the current needed in the level shifting resistors to maintain the same resistance level at the base of the output emitter-follower as was achieved for the triple design. To realize the $1.07 \mathrm{k} \Omega$ equivalent resistance from the base of $Q_{4}$ to ground in Fig. 5.6, the de current needed is .667 mA and the resistor values are $R_{3}=1.5 \mathrm{k} \Omega$ and $\mathrm{R}_{4}=3.75 \mathrm{k} \Omega$. As for the triple design, a 1 mA current is specified in the output emitter-follower, corresponding to $R_{5}=6 \mathrm{k} \Omega$.

The differential-mode half-circuit suitable for determining the differential frequency response of the amplifier in Fig. 5.6 is given in Fig. 5.7. The emitter-follower, $Q_{3}$, is included in the half circuit because it is contained within the feedback loop and, therefore, significantly influences the amplifier response. As indicated in Figs. 5.6 and 5.7, compensation is achieved for the pair with a capacitor, $C_{f}$, in shunt with the feedback resistor $R_{f}$. Unlike the series-series triple, the pair cannot, in general, be compensated without the addition of an actual capacitive element.

The design variables for the series-shunt pair amplifier of Fig. 5.6 are the feedback resistors $R_{e}$ and $R_{f}$, and the feedback capacitance, $C_{f}$; the differential collector load resistors, $R_{1}$ and $R_{2}$, which can be adjusted by introducing common-mode resistors; the dc currents in $Q_{1}$, and $Q_{2}$ and $Q_{3}$ as governed by $R_{6}$ and the ratio of currents in $Q_{5}$ and $Q_{6}$; and the device geometry variables for $Q_{1}, Q_{2}$ and $Q_{3}$. The design constraints are: 1) all passive elements must be nonnegative, 2) the 1.4 V collector-emitter voltage for $Q_{1}$, 3) the 2.4 volt de level at the collector of $Q_{2}$, 4) the upper bound on the differential collector load resistances, 5) the dc voltage drop across $R_{f}$, through which part of the current in $Q_{3}$ is drawn, 6) for each


Fig. 5.7: Differential-mode half circuit for the basic pair in the amplifier of Fig. 5.6.
side of the balanced configuration, a total quiescent current of 3 nA available to $Q_{1}, Q_{2}$ and $Q_{3}, 7$ ) the drain of .667 mA from the emitter current of $Q_{3}$ through the level shifting resistors, and 8) a minimum emitter stripe length of 0.6 mil for $Q_{1}, Q_{2}$ and $Q_{3}$.

### 5.5 Other Triple•Designs, T2-T4

Complete amplifier designs based on the configurations T2, T3 and T4 are shown in Figs. 5.8, 5.9 and 5.10, respectively. These designs are all quite similar to that presented in Fig. 5.3 for the configuration $T 1$, except that the common-mode current source, $Q_{8}$, must be added to supply the current for the third stage transistor, Q3. Also, the differing connections of the feedback resistor $R_{f}$ impose different constraints on the variables in the design optimization procedure for each configuration. Frequency compensation, if necessary, can be achieved for the amplifiers of Figs. 5.8 and 5.10 with a shunt capacitance across $R_{f}$. The shunt-series pair in Fig. 5.9 can be compensated in the same manner as used for the series-series triple in Fig. 5.3; no capacitive element should be needed.

Except for the current source biasing, the dc design is essentially the same for all of the triple amplifiers. A 1.4 V collector-emitter voltage is specified for $Q_{1}$ and $Q_{2}$, and the level shifting and output stage design is identical to that used in the amplifier of Fig. 5.3. As for the amplifier of Fig. 5.3, the current source biasing leads to a relatively insensitive voltage level at the collector of $Q_{3}$.

### 5.5.1 Configuration T2

The amplifier of Fig. 5.8 is based on the feedback configuration T 2 in Fig. 5.1. This configuration is a series-shunt overall feedback pair
followed by a local series feedback stage. The dc constraint imposed on the feedback resistor $R_{f}$ in Fig. 5.8 is that the current in $R_{f}$ must be drawn through the interstage resistor $R_{2}$. The voltage drop across $R_{f}$ is higher, by the base-emitter junction of $Q_{3}$, than in Fig. 5.3.

### 5.5.2 Configuration T3

A complete amplifier based on configuration T 3 is shown in Fig. 5.9. For the basic configuration, a local series feedback input stage is followed by an overall shunt-series feedback pair. If a forward biased base-emitter voltage of .7 volts is assumed for $Q_{2}$ and $Q_{3}$ in Fig. 5.9, then there is no dc current in $R_{f}$; hence this resistor may be adjusted without regard to dc conditions and the constraint associated with $R_{f}$. in all of the other configurations is eliminated.

### 5.5.3 Configuration T4

The amplifier in Fig. 5.10 is based on the configuration $T 4$, a series-shunt-series local feedback cascade. The dc current in the resistor $\mathrm{R}_{\mathrm{f}}$ is drawn through the resistor $R_{2}$ and sinked by the collector of $Q_{1}$. It is possible to eliminate the resistor $R_{1}$ and supply all of the first stage collector current through $R_{f}$. This is, in fact, the condition specified by the design optimization results of the next chapter.

### 5.6 Other Pair Designs

Shown in Figs. 5.11, 5.12 and 5.13 are complete amplifier designs based on the pair configurations P2, P3 and P4. These designs are essentially the same as that used for the series-shunt pair in Fig. 5.3, except for the different connections of the feedback resistor $R_{f}$. The same form of current source biasing is used in all of the pair designs and leads to

Fig. 5.8: Complete amplifier design based on configuration T.2.

Fig. 5.9: Complete amplifier design based on configuration T 3.

Fig. 5.10: Complete amplifier design based on configuration T 4.
an insensitive voltage level at the collector of $Q_{2}$. A collectoremitter voltage of 1.4 V is specified for the first stage transistor, $\mathrm{Q}_{1}$. The level shifting and output stage design in Figs. 5.11-5.13 is identical to that used in Fig. 5.6 except that for Figs. 5.11 and 5.13 the current in the emitter follower $Q_{3}$ does not include the de current in $R_{f}$. Frequency compensation cán if needed, be established with a shunt capacitor across $R_{f}$ in all of the configurations.

### 5.6.1 Configuration P2

The amplifier in Fig. 5.11 is based on the configuration P2, a seriesshunt overall feedback pair. Unlike the configuration P1, the emitterfollower is not included within the feedback loop. As a result, in Fig. 5.11 the dc voltage drop across $R_{f}$ is somewhat higher than in Fig. 5.6, and the de current in $R_{f}$ must be drawn through the resistor $R_{2}$. In Fig. 5.11, the current in the emitter-follower $Q_{3}$ is simply the de current of .667 mA needed in the level shifting stage. A total current of 2.33 mA is thus available to $Q_{1}$ and $Q_{2}$.

### 5.6.2 Configuration P3.

The amplifier in Fig. 5.12 is based on configuration P3, a local series-shunt feedback cascade with the emitter-follower $Q_{3}$ included in the local shunt feedback loop. The current in $R_{f}$ is drawn from the emitter of $Q_{3}$ and fed to the collector of $Q_{1}$. It would be possible to provide all of the first stage collector current through $R_{f}$; this, however, is not the optimum situation indicated by the results in Sec. 6.2.3.


Fig. 5.11: Complete amplifier design based on configuration P2.

Fig. 5.12: Complete amplifier design based on configuration P3.

Fig. 5.13: Complete amplifier design based on configuration P4.

### 5.6.3 Configuration P4

A complete amplifier design based on configuration P4 is shown in Fig. 5.13. The basic configuration is a local series-shunt feedback cascade with the emitter-follower not included in the shunt feedback loop. The dc current in $R_{f}$ is drawn through $R_{2}$ rather than from the emitter of $Q_{3}$. As for the design of Fig. 5.12, the resistor $R_{1}$ can be eliminated, but the automated design results indicate this is not the optimum design situation.

## CHAPTER VI

DESIGN OPTIMIZATION RESULTS

### 6.1 Introduction

The complete amplifier designs developed in Chapter V have been optimized using the program ADOP to achieve the maximum possible -3dB bandwidth for each design. The results of the optimization procedure are presented in this chapter and are used to compare the effectiveness of the basic feedback configurations first introduced in Chapter II and repeated in Fig. 5.1.

The complete amplifier designs proposed in Chapter $V$ are based on the specification of a 34 dB low-frequency voltage gain, $\pm 6 \mathrm{~V}$ power supplies, and a total quiescent power dissipation of 96 mW . These specifications represent the overall constraints in the design optimization procedure. Additional constraints arising from dc conditions, device geometry considerations, and the design of the level shifting and output stages are presented in Chapter $V$ in the course of developing the complete amplifier designs.

Two constraints arising from monolithic processing considerations are also included in the design procedure. First, the minimum value allowed for a diffused resistor is $50 \Omega$. This limitation is relevant only to the series emitter feedback resistors; it is imposed because these resistors must match and track other larger feedback resistors if low gain sensitivity to processing and environment is to be achieved. For values below the minimum resistance, contact effects make such matching
increasingly difficult to establish. The second design constraint arising from processing considerations is that the series emitter resistors in the first and third stages of the triples, Tl-T4, be equal. This condition is imposed to ensure good matching between these relatively small resistors. Since the gain of the triples depends strongly on the four diffused resistors $R_{e l}, R_{e 2}, R_{f}$ and $R_{3}$, the constraint $R_{e 1}=R_{e 2}$ reduces the need for accurately matching unequal resistors from four to three values of resistance.

For the optimum amplifier designs presented in this chapter, the firstorder temperature dependence of both the low-frequency voltage gain and quiescent output voltage has been investigated using the nonlinear de circuit analysis program BIAS-3 [50]. The principal effects considered in the analysis are the first-order temperature sensitivities of the diffused resistors and transistor $\beta_{0}$ 's. Values of $2000 \mathrm{ppm} /{ }^{\circ} \mathrm{C}$ and $6600 \mathrm{ppm} /{ }^{\circ} \mathrm{C}$ at room temperature are assumed, respectively, for these sensitivities [51]; variations in the gain and dc output voltage are then determined over the full temperature range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$. The assumption of a linear temperature dependence over this full range for the resistances values $\beta_{0}$ is, of course, in error. However, the deviation from a linear dependence is typically less than $10 \%$; consequently, the analysis does provide a suitable, basis for comparing the first-order temperatures sensitivities of the optimum designs. It is reasonable to assume that the temperature dependence in an actual realization of any of the designs is influenced less by nonlinear components of the resistance and $\beta_{0}$ temperature dependence, than by the variation of resistance ratios with temperature. This latter effect is difficult to predict and can be effectively incorporated in a
design procedure only on the basis of an extensive characterization of the processing to be used.

### 6.2 Optimum Pair Designs

### 6.2.1 Configuration P1

The design optimization results for the amplifier of Fig. 5.6, which is based on configuration P1, are summarized in Fig. 6.1 and Tables VI. 2 $a, b$ and $c$. The frequency responses represented by the dashed lines in the figure correspond to several designs that were used as starting points in the optimization procedure. Component values and current levels for two of the initial designs (denoted by (1) and (2) are given in Tables VI.2a and $b$. For both of these initial designs, $Q_{1}, Q_{2}$ and $Q_{3}$ are single emitter, single base contact structures with an emitter stripe length of 1.0 mil . All of the design runs converged to the same optimum design. The frequency response for this optimum is indicated by the solid line in Fig. 6.1.

The optimum Pl design provides the specified low-frequency voltage gain of 34 dB and has -3 dB bandwidth of 123 MHz . As indicated in Fig. 6.1, a near maximally flat magnitude frequency response is achieved. The bandwidth is the second largest obtained for designs presented in this chapter; it is exceeded only by the 133 MHz bandwidth of the optimum T 3 design. As brought out in the comparison of Sec. 6.4, however, the optimum PI design provides the best overall performance of any of the designs considered.

The passive element values for the optimum P1 design are given in Table VI.2a. The values shown for the differential collector load resistances, $R_{1}$ and $R_{2}$, are the maximum allowed by dc conditions. This situation is the case for all of the pair designs; consequently, the


TABLE VI.la

COMPONENT VALUES AND CURRENT LEVELS FOR INITIAL DESIGN (1) IN FIG. 6.1

$$
\begin{array}{ll}
\mathrm{R}_{\mathrm{e}}=250 \Omega & \mathrm{R}_{6}=3.1 \mathrm{k} \Omega \\
\mathrm{R}_{\mathrm{f}}=2.4 \mathrm{k} \Omega & \\
\mathrm{R}_{1}=10.6 \mathrm{k} \Omega & C_{f}=0 \\
R_{2}=4.2 \mathrm{k} \Omega & \\
I_{C}\left(Q_{1}\right)=.5 \mathrm{~mA} & \mathrm{I}_{\mathrm{C}}\left(Q_{5}\right) \\
I_{C}\left(Q_{2}\right)=.85 \mathrm{~mA} & \mathrm{I}_{\mathrm{C}}\left(Q_{6}\right)
\end{array}
$$

## TABLE VI.1b

## COMPONENT VALUES AND CURRENT LEVELS

 FOR INITIAL DESIGN (2) IN FIG. 6.1$$
\begin{array}{ll}
R_{e}=67 \Omega & R_{6}=2.5 \mathrm{k} \Omega \\
R_{f}=9.1 \mathrm{k} \Omega & \\
R_{1}=5.3 \mathrm{k} \Omega & C_{f}=.5 \mathrm{pF} \\
R_{2}=3.4 \mathrm{k} \Omega & \\
I_{C}\left(Q_{1}\right)=1 \mathrm{~mA} & \mathrm{I}_{\mathrm{C}}\left(Q_{5}\right) \\
I_{C}\left(Q_{2}\right)=1.07 \mathrm{~mA} & \mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{6}\right)
\end{array}
$$

TABLE VI.2a
PAŚSIVE ELEMENT VALUES FOR OPTIMUM PI DESIGN

$$
\begin{array}{ll}
R_{e}=50 \Omega & \\
R_{f}=3.5 \mathrm{k} \Omega & R_{6}=4.5 \mathrm{k} \Omega \\
R_{1}=50 \mathrm{k} \Omega & C_{f}=.3 \mathrm{pF} \\
R_{2}=6.2 \mathrm{k} \Omega &
\end{array}
$$

TABLE VI.2b
DEVICE SPECIFICATIONS FOR OPTIMUM PI DESIGN

| Device | $n_{e}$ | $n_{b}$ | $e^{, m i l s}$ | $I_{C}, \mathrm{~mA}$ | $f_{t}, \mathrm{MHz}$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{Q}_{1}$ | 1 | 2 | 1.07 | 1.06 | 580 |
| $\mathrm{Q}_{2}$ | 1 | 1 | .6 | .58 | 560 |
| $\mathrm{Q}_{3}$ | 1 | 1 | .6 | 1.36 | 640 |
| $\mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{5}\right) / \mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{6}\right)=2.99$ |  |  |  |  |  |

TABLE VI.2c
TEMPERATURE DEPENDENCE OF GAIN AND DC OUTPUT VOLTAGE FOR P1 DESIGN

| $\mathrm{T},{ }^{\circ} \mathrm{K}$ | $\mathrm{A}_{\mathrm{V}}(0)$ | $\mathrm{V}_{0}, \mathrm{mV}$ |
| :--- | :--- | :--- |
| 218 | 49.21 | -116 |
| 258 | 49.46 | -90 |
| 300 | 49.52 | -88 |
| 348 | 49.51 | -96 |
| 398 | 49.46 | -110 |

maximum theoretically available voltage swing at the output of these amplifiers is, in all cases, $\pm 2.4$ volts.

A compensation capacitance, $\mathrm{C}_{\mathrm{f}}$, of 0.3 pF is specified in Table VI. 2 a . This capacitance can be realized with a base-collector junction area of $5 \mathrm{mil}^{2}$ under a reverse bias of approximately 6 volts. The Pl amplifier is the only configuration for which a feedback capacitance is needed in the optimum design. The amplifier can be optimized under the constraint $C_{f}=0$, but the maximum bandwidth obtainable is then reduced to 100 MHz .

The device specifications for the optimum Pl design are presented in Table VI. 2 b . The optimum geometry and dc current level are given for each of the transistors $Q_{1}, Q_{2}$ and $Q_{3}$, and the transistor $f_{T}$ corresponding to these conditions is included in the table. Minimum area, single base contact geometries are specified for both $Q_{2}$ and $Q_{3}$; the optimum geometry for $Q_{1}$ is a single emitter, double base contact device with an emitter stripe length of 1.07 mil . Also given in Table VI. 2 b is the ratio of quiescent currents in the current source transistors, $Q_{5}$ and $Q_{6}$, that is needed to establish the optimum distribution of dc current among $Q_{1}, Q_{2}$ and $Q_{3}$; the ratio $I_{C}\left(Q_{5}\right) / I_{C}\left(Q_{6}\right) \simeq 3.0$ is specified.

Analysis results for the first-order temperature dependence of gain and de output voltage in the optimum Pl design are given in Table VI.2c. The estimated total variation in the low-frequency voltage gain over the temperature range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ is only $.6 \%$ of the gain value at room temperature. This variation is the lowest obtained for the designs considered; it corresponds to an average sensitivity of $33 \mathrm{ppm} /{ }^{\circ} \mathrm{C}$. This very low dependence on temperature is due to a relatively high loop gain for the P1 configuration and to the fortuitous existence of a first-order
zero in the gain sensitivity near room temperature.
The quiescent output voltage of the optimum Pl design also exhibits a first-order sensitivity zero near room temperature. As a result, the total variation in this voltage is less than 30 mV over the $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ temperature range. This is the lowest output level drift obtained for any of the amplifiers considered.

### 6.2.2 Configuration P2

The frequency response of the optimum design for the amplifier in Fig. 5.11, which is based on configuration P 2 , is included in Fig. 6.2. The maximum bandwidth for this configuration is 95 MHz , the lowest value obtained for any of the designs based on a pair configuration.

The P2 configuration is an overall series-shunt feedback pair where, in contrast to the Pl amplifier, the output emitter-follower is not included within the feedback loop. The maximum bandwidth for the P2 design is $23 \%$ less than that for the Pl configuration, indicating that a substantial improvement is gained by including the emitter-follower within the overall feedback loop.

The passive component values for the optimum P2 design are given in Table VI. 3a. As for the other pair designs, the optimum values for $R_{1}$ and $\mathrm{R}_{2}$ are the maximum allowed by dc condtions. No compensation capacitance is needed for the optimum design.

The device specifications are given in Table VI.3b for the optimum P2 design. As for the P1 configuration, minimum area structures are specified for $Q_{2}$ and $Q_{3}$, while a single emitter, double base contact device is optimum for $Q_{1}$. The emitter stripe length for $Q_{1}$ is 1.23 mil . The ratio of currents in the current source devices is $I_{C}\left(Q_{5}\right) / I_{C}\left(Q_{6}\right)=2.43$.


Fig. 6.2: Frequency response of optimum designs for configurations P2, P3, and P4.

TABLE VI. 3 a
passive elfemint valuis for optimum p2 design

| $R_{e}=53 \Omega$ | $R_{6}=3.0 \mathrm{k} \Omega$ |
| :--- | :--- | :--- |
| $R_{f}=3.9 \mathrm{k} \Omega$ |  |
| $R_{1}=6.1 \mathrm{k} \Omega$ | $C_{f}=0$ |
| $R_{2}=2.5 \mathrm{k} \Omega$ |  |

TABLE VI. 3 b
DEVICE SPECIFICATIONS FOR OPTIMUM P2 DESIGN

| Device | $n_{e}$ | $n_{b}$ | $\ell_{e}, \mathrm{mils}$ | $I_{C}, \mathrm{~mA}$ | $f_{t}, \mathrm{MHz}$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{Q}_{1}$ | 1 | 2 | 1.23 | .87 | 530 |
| $Q_{2}$ | 1 | 1 | .6 | .68 | 575 |
| $Q_{3}$ | 1 | 1 | .6 | .67 | 580 |
| $I_{C}\left(Q_{5}\right) / I_{C}\left(Q_{6}\right)=2.43$ |  |  |  |  |  |

TABLE VI.3c
TEMPERATURE DEPENDENCE OF GAIN AND DC OUTPUT VOLTAGE FOR P2 DESIGN

| $T,{ }^{\circ} \mathrm{K}$ | $\mathrm{A}_{\mathrm{V}}(0)$ | $\mathrm{V}_{0}, \mathrm{mV}$ |
| :--- | :--- | :--- |
| 218 | 48.99 | -350 |
| 258 | 49.77 | -180 |
| 300 | 49.98 | -23 |
| 348 | 49.94 | +138 |
| 398 | 49.73 | +289 |

The analysis results for the first-order temperature dependence of the P2 design are given in Table VI.3c. The total gain variation over $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ is $2.0 \%$ of the nominal value. As for the Pl design, a first-order zero in the gain sensitivity exists near room temperature. However, the lower loop gain of the P2 design results in a somewhat larger total variation in the gain. A.higher loop gain is obtainable for the Pl design because the inclusion of the emitter-follower within the feedback loop significantly reduces the loading of the feedback network on the forward amplifier.

The total drift in the output dc level for the P 2 amplifier is 640 mV over the range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$. This is the largest drift exhibited by any of the designs considered and is more than an order of magnitude greater than that obtained for the Pl design.

### 6.2.3 Configuration P3

The design results for the amplifier for Fig. 5.12, which is based on configuration P3, are given in Fig. 6.2 and Tables VI. 4 a,b, and c. The basic configuration is a series-shunt cascade with the emitter-follower included in the feedback loop of the shunt stage. The bandwidth of the optimum P3 design is 122 MHz , almost identical to the optimum bandwidth for the Pl amplifier. The sensitivity to temperature is, however, considerably higher for the local feedback cascade. The total variation in gain over the range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ is $10.2 \%$ of the room temperature value and the total drift in the dc output voltage level over this temperature range is 190 mV .

The passive elements and device specifications for the optimum P3 design are given in Tables VI. $4 a$ and $b$. The values for $R_{1}$ and $R_{2}$ on the

TABLE VI. 4a

PASSIVE ELEMENT VALUES FOR OPTIMUM P3 DESIGN

| $R_{e}$ | $=50 \Omega$ |  |
| :--- | :--- | :--- |
| $R_{f}$ | $=5.1 \mathrm{k} \Omega$ | $R_{6}=2.5 \mathrm{k} \Omega$ |
| $R_{1}$ | $=4.9 \mathrm{k} \Omega$ | $C_{f}=0$ |
| $R_{2}$ | $=3.4 \mathrm{k} \Omega$ |  |

TABLE VI. 4b
DEVICE SPECIFICATIONS FOR OPTIMUM P3 DESIGN

| Device | $n_{e}$ | $n_{b}$ | $\ell_{e}, m i l s$ | $I_{C}, m A$ | $f_{t}, M H z$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $Q_{1}$ | 1 | 2 | .92 | 1.28 | 590 |
| $Q_{2}$ | 1 | 1 | .6 | 1.05 | 516 |
| $Q_{3}$ | 1 | 1 | .6 | .86 | 605 |
| $I_{C}\left(Q_{5}\right) / I_{C}\left(Q_{6}\right)=1.21$ |  |  |  |  |  |

TABLE VI.4c
TEMPERATURE DEPENDENCE OF GAIN AND DC OUTPUT VOLTAGE FOR P3 DESIGN

| $\mathrm{T},{ }^{\circ} \mathrm{K}$ | $\mathrm{A}_{\mathrm{V}}(0)$ | $\mathrm{V}_{0}, \mathrm{mV}$ |
| :--- | :--- | :--- |
| 218 | 51.24 | +42 |
| 258 | 50.58 | +8 |
| 300 | 49.29 | -35 |
| 348 | 47.71 | -87 |
| 398 | 46.11 | -144 |

maximum allowed by dc conditions, and no compensation capacitance is needed for the optimum design. A minimum area geometry is optimum for both $Q_{2}$ and $Q_{3}$, while a double base contact device is specified for $Q_{1}$, with a stripe length of .92 mil . The current ratio in the common-mode transistors $Q_{5}$ and $Q_{6}$ is $I_{C}\left(Q_{5}\right) / I_{C}\left(Q_{6}\right)=1.21$ for the optimum design. The difference in performance between the optimum designs based on the P1 and P3 configurations is essentially that expected from a consideration of ideal feedback systems [52]. Though comparable bandwidths are obtainable for similar local and overall feedback configurations, the latter represents a more efficient use of feedback and results in a significantly greater reduction in gain sensitivity.

### 6.2.4 Configuration P4

The design optimization results for the P4 amplifier of Fig. 5.13 are given in Fig. 6.2 and Tables VI. $5 \mathrm{a}, \mathrm{b}$ and c . The basic configuration is a local series-shunt cascade followed by an emitter-follower. The bandwidth for the optimum design is 105 MHz , $14 \%$ below the maximum bandwidth for the P3 configuration, a local feedback cascade with the emitter follower included in the shunt feedback loop.

The maximum allowed values are optimum for the resistors $R_{1}$ and $R_{2}$ in the P3 design. No compensation capacitance is needed. The optimum geometry for the transistor $\mathrm{Q}_{1}$ is a device with two emitters, three base contacts, and an emitter stripe length of 1.3 mil. A minimum area structure is optimum for $Q_{2}$, and for $Q_{3}$ a single emitter, single base contact device is specified, with an emitter stripe length of 1.2 mil . The current ratio in the source transistors is $I_{C}\left(Q_{5}\right) / I_{C}\left(Q_{6}\right)=2.44$.

## TABLE VI.5a

## PASSIVE ELEMENT VALUES FOR OPTIMUM P4 DESIGN

$$
\begin{array}{ll}
R_{e}=50 \Omega & R_{6}=3.9 \mathrm{k} \\
R_{f}=5.1 \mathrm{k} \Omega & \\
R_{1}=4.0 \mathrm{k} \Omega & C_{f}=0 \\
R_{2}=3.6 \mathrm{k} \Omega &
\end{array}
$$

TABLE VI.5b
DEVICE SPECIFICATIONS FOR OPTIMUM P4 DESIGN

| Device | $n_{e}$ | $n_{b}$ | $\ell_{e}, m i l s$ | $I_{C}, m A$ | $f_{t}, M H z$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $Q_{1}$ | 2 | 3 | 1.33 | 1.65 | 520 |
| $Q_{2}$ | 1 | 1 | .6 | .68 | 575 |
| $Q_{3}$ | 1 | 1 | 1.22 | .67 | 520 |
|  |  |  |  |  |  |

TABLE VI.5c
TEMPERATURE DEPENDENCE OF GAIN AND DC OUTPUT VOLTAGE FOR P4 DESIGN

| $T,{ }^{\circ} \mathrm{K}$ | $A_{V}(0)$ | $\mathrm{V}_{0}, \mathrm{mV}$ |
| :--- | :--- | :--- |
| 218 | 51.70 | +73 |
| 258 | 51.46 | +38 |
| 300 | 50.40 | +1 |
| 348 | 48.94 | -41 |
| 398 | 47.41 | -84 |

The total variation in the low-frequency voltage gain for the optimum P4 design is $8.6 \%$ over the range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$. The drift in the quiescent output level over this temperature range is 160 mV .
6.3 Optimum Triple Designs
6.3.1 Configuration T1.

The amplifier of Fig. 5.3 is based on configuration $T 1$, an overall series-series feedback triple. The design optimization results for this amplifier are given in Fig. 6.3 and Tables VI. $6 \mathrm{a}, \mathrm{b}$ and c . In the figure, the dashed-line responses correspond to designs used as starting points in the optimization procedure. All of the design runs converged to the optimum, represented by the solid line response.

The optimum design for the Tl amplifier provides the specified voltage gain of 34 dB and has a -3 dB bandwidth of 90 MHz . This bandwidth is the same as that obtained for the T 4 design described in Sec. 6.3.4, but it is substantially below the optimum bandwidth of 133 MHz obtained for the T3 configuration.

Passive element values for the optimum Tl design are listed in Table VI.6a. The values of the differential collector load resistors R1 and R2 are the maximum allowed by dc conditions. For the third stage in triple, the common-mode resistance $R_{8}=1.1 \mathrm{k} \Omega$ is introduced to establish the optimum value of $2.1 \mathrm{~K} \Omega$ for the differential load, $R_{3}$, on the stage. Unlike the second, or output, gain stage in the pairs, the third gain stage in the triples is a series feedback stage. As a result, the load on the stage has an important influence on the frequency response; for all of the triples, the optimum value of $R_{3}$ is less than the maximum permitted by dc conditions. The need for the common-mode resistor $R_{8}$ in all

Fig. 6.3: Frequency response of optimum design for configuration Tl.

## TABLE VI.6a

PASSIVE ELEMENT VALUES FOR OPTIMUM TI DESIGN

$$
\begin{array}{ll}
R_{e l}=R_{e 2}=270 \Omega & R_{1}=11.0 \mathrm{k} \Omega \\
R_{f}=2.0 \mathrm{k} \Omega & R_{2}=5.6 \mathrm{k} \Omega \\
R_{3}=2.1 \mathrm{k} \Omega & R_{7}=3.1 \mathrm{k} \Omega \\
C_{f}=0 & R_{8}=1.1 \mathrm{k}
\end{array}
$$

TABLE VI.6b
DEVICE SPECIFICATIONS FOR OPTIMUM T1 DESIGN

| Device | $n_{e}$ | $n_{b}$ | $\ell_{e}, m i l s$ | $I_{C}, m A$ | $f_{t}, \mathrm{MHz}$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{Q}_{1}$ | 1 | 1 | 1.05 | .48 | 475 |
| $\mathrm{Q}_{2}$ | 1 | 1 | .93 | .83 | 560 |
| $\mathrm{Q}_{3}$ | 1 | 1 | .69 | .69 | 565 |
| $\mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{6}\right) / \mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{7}\right)=1.35$ |  |  |  |  |  |

TABLE VI. $6 c$
TEMPERATURE DEPENDENCE OF GAIN AND DC OUTPUT VOLTAGE IN P4 DESIGN

| $\mathrm{T},{ }^{\circ} \mathrm{K}$ | $\mathrm{A}_{\mathrm{V}}(0)$ | $\mathrm{V}_{0}, \mathrm{mV}$ |
| :--- | :--- | :--- |
| 218 | 48.67 | +118 |
| 258 | 49.18 | +134 |
| 300 | 49.48 | +154 |
| 348 | 49.65 | +187 |
| 398 | 49.73 | +221 |

of the triple designs limits the available unclipped output voltage swing for these amplifiers to values significantly below the $\pm 2.4 \mathrm{~V}$ achieved for all of the pair designs described in Sec. 6.2. For the optimum T 1 design, the maximum unclipped swing is $\pm 1.5 \mathrm{~V}$, the largest obtained for any of the triples.

The optimum series emitter resistance, $R_{e 1}=R_{e 2}$, for $T 1$ amplifier is $270 \Omega$. This is the largest value obtained for any of the designs considered. Because of this relatively large value for the smallest diffused resistors, the optimum T design is comparatively easy to realize monolithically. As pointed out in Sec. 5.3, no feedback capacitor is needed to compensate the Tl configuration.

The device specifications for the optimum Tl design are given in Table VI.5b. A single emitter, single base contact structure is optimum for $Q_{1}, Q_{2}$ and $Q_{3}$; the emitter stripe lengths are $1.05 \mathrm{mil}, .93 \mathrm{mil}$, and .69 mil , respectively. The ratio of currents in the current source transistors $Q_{6}$ and $Q_{7}$ is $I_{C}\left(Q_{6}\right) / I_{C}\left(Q_{7}\right)=1.35$ for the optimum design.

Analysis results for the first-order temperature dependence of gain and output level in the optimum Tl design are given in Table VI.6c. The total gain variation over the temperature range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ is $2.1 \%$ of the room temperature gain. This is by far the lowest temperature sensitivity obtained for any of the triple designs and reflects the relatively high loop gain obtained with the series-series triple. For all of the other triples, at least two feedback loops are cascaded and the sensitivity to temperature is relatively high.

The total drift in the quiescent output voltage for the $T 1$ design is 100 mV over the $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ range. Of the designs considered, this
performance is exceeded only by the 30 mV drift obtained for the Pl configuration.

### 6.3.2 Configuration T2

The frequency response for the optimum design of the amplifier in Fig. 5.8, which is based on configuration T2, is included in Fig. 6.4. The maximum - 3 dB bandwidth for this amplifier is 78 MHz , the lowest of the designs considered.

The passive element values for the optimum T2 design are given in Table VI.7a. Because of very low current in the third stage, a high value of $R_{8}$ is needed and the unclipped output voltage swing is limited to $\pm 0.13$ volts.

The low third stage current results from the need to drain a substantial current through the feedback resistor $R_{f}$. This current is larger for the triple configuration than for the corresponding pair design of Fig. 5.11, even though the latter has a larger voltage drop across $R_{f}$, because the optimum values for $R_{f}$ are generally smaller for the triple designs than for the pairs. As for all of the triples, the optimum collector load resistors for the first two stages, $R_{1}$ and $R_{2}$, are the maximum permitted by dc conditions; also, no compensation capacitance is needed.

The device characteristics for the optimum T2 design are given in Table VI.7b. A minimum area structure is optimum for all of the devices, $Q_{1}, Q_{2}$ and $Q_{3}$, in the basic feedback configuration. Three current source transistors are needed in the $T 2$ amplifier because, unlike the $T 1$ design, a separate current source must be provided for the third stage of the triple. The ratios of quiescent currents in the transistors $Q_{6}$ and $Q_{8}$ to the current in the diode connected transistor, $Q_{7}$, are $I_{C}\left(Q_{6}\right) / I_{C}\left(Q_{7}\right)=3.39$


Fig. 6.4: Frequency response of optimum designs for configurations T2, T3, and T4.

TABLE VI.7a
passive element values for optimum t2 design

| $R_{e l}=R_{e 2}=120 \Omega$ | $R_{1}=9.3 \mathrm{k} \Omega$ |
| :--- | :--- | :--- |
| $R_{f}=2.3 \mathrm{k} \Omega$ | $R_{2}=3.4 \mathrm{k} \Omega$ |
| $R_{3}=1.9 \mathrm{k} \Omega$ | $R_{7}=6.0 \mathrm{k} \Omega$ |
| $C_{f}=0$ | $R_{8}=21.4 \mathrm{k} \Omega$ |

TABLE VI.7b
DEVICE SPECIFICATIONS FOR OPTIMUM T2 DESIGN

| Device | $\mathrm{n}_{\mathrm{e}}$ | n | mi | ${ }_{C}$, m | ${ }_{t}, \mathrm{MHz}$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $Q_{1}$ | 1 | 1 | . 6 | . 57 | 550 |
| $Q_{2}$ | 1 | 1 | . 6 | . 44 | 520 |
| $Q_{3}$ | 1 | 1 | . 6 | . 07 | 225 |
| $\begin{aligned} & I_{C}\left(Q_{6}\right) / I_{C}\left(Q_{7}\right)=3.39 \\ & I_{C}\left(Q_{8}\right) / I_{C}\left(Q_{7}\right)=.152 \end{aligned}$ |  |  |  |  |  |

TABLE VI.7c
TEMPERATURE DENPENDENCE OF GAIN AND DC OUTPUT VOLTAGE FOR T2 DESIGN

| $\mathrm{T},{ }^{\circ} \mathrm{K}$ | $\mathrm{A}_{\mathrm{V}}(0)$ | $\mathrm{V}_{0}, \mathrm{mV}$ |
| :--- | :--- | :--- |
| 218 | 58.53 | -317 |
| 258 | 53.41 | -240 |
| 300 | 48.32 | -201 |
| 348 | 43.37 | -176 |
| 398 | 39.09 | -160 |

and ${ }^{1} C\left(Q_{8}\right) / I_{C}\left(Q_{7}\right)=.16$ for the optimum design.
The temperature dependence of the gain and dc output level for the optimum T2 design is given in Table VI.7c. Over the temperature range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$, the total variation in the low-frequency gain is $\mathbf{3 8 . 8 \%}$ and the total drift of the output voltage level is 160 mV . The sensitivity of the gain to temperature in the T 2 design is exceeded only by that of the amplifier based on configuration T 4 , a series-shunt-series local feedback cascade.

### 6.3.3 Configuration T3

Design results for the amplifier based on configuration $T 3$, and shown in Fig. 5.9, are given in Fig. 6.4 and Tables VI. $8 \mathrm{a}, \mathrm{b}$, and c . The -3 dB bandwidth of 133 MHz for the optimum design is the largest obtained for any of the amplifiers considered.

The amplifier based on configuration T 3 is unique with respect to the other designs in that no de current flows through the feedback resistor $R_{f}$. As a result, this resistor can be adjusted without affecting the dc conditions. The optimum value of $\mathrm{R}_{\mathrm{f}}$ given in Table VI.8a is significantly lower than the values for the other designs, indicating that dc constraints on $R_{f}$ may degrade the bandwidth in the other amplifiers. Of the configurations considered, it is generally practical to establish a dc independent $R_{f}$ only for the T3 configuration.

The resistor values and device specifications for the optimum design are given in Tables VI.8a and $b$. The values of $R_{1}$ and $R_{2}$ are the maximum allowed. The available unclipped voltage swing at the amplifier output is $\pm .9$ volts, the second largest value obtained for the triple designs. The optimum device geometries are single emitter, single base contact

## TABLE VI.8a

## PASSIVE ELEMENT VALUES FOR OPTIMUM T3 DESIGN

$$
\begin{array}{ll}
R_{e l}=R_{e 2}=62 \Omega & R_{1}=9.1 \Omega \\
R_{f}=280 \Omega & R_{2}=5.6 \mathrm{k} \Omega \\
R_{3}=1.5 \mathrm{k} \Omega & R_{7}=3.2 \mathrm{k} \Omega \\
C_{f}=0 & R_{8}=1.8 \mathrm{k} \Omega
\end{array}
$$

TABLE VI. 8 b
DEVICE SPECIFICATIONS FOR OPTIMUM T3 DESIGN

| Device | $n_{e}$ | $n_{b}$ | $\ell_{e}, \mathrm{mils}$ | $\mathrm{I}_{\mathrm{C}}, \mathrm{mA}$ | $\mathrm{f}_{\mathrm{t}}, \mathrm{MHz}$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{Q}_{1}$ | 1 | 2 | 2.40 | .58 | 385 |
| $\mathrm{Q}_{2}$ | 1 | 1 | .6 | .82 | 590 |
| $\mathrm{Q}_{3}$ | 1 | 1 | .66 | .60 | 555 |
|  |  |  |  |  |  |
|  | $\mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{6}\right) / \mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{7}\right)=.71$ |  |  |  |  |
|  | $\mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{8}\right) / \mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{7}\right)=.73$ |  |  |  |  |

TABLE VI.8c
TEMPERATURE DEPENDENCE OF GAIN AND DC OUTPUT VOLTAGE FOR T3 DESIGN

| $\mathrm{T},{ }^{\circ} \mathrm{K}$ | $\mathrm{A}_{\mathrm{V}}(0)$ | $\mathrm{V}_{0}, \mathrm{mV}$ |
| :--- | :--- | :--- |
| 218 | 53.36 | +63 |
| 258 | 51.89 | -54 |
| 300 | 49.88 | +160 |
| 348 | 47.64 | +273 |
| 398 | 45.53 | +389 |

structures for $Q_{2}$ and $Q_{3}$ and a single emitter, double base contact device for $Q_{1}$; the emitter stripe lengths are $2.4 \mathrm{mil}, .6 \mathrm{mil}$, and .66 mil , respectively, for $Q_{1}, Q_{2}$, and $Q_{3}$. The current ratios in the common-mode source transistors of the optimum $T 3$ design are $I_{C}\left(Q_{6}\right) / I_{C}\left(Q_{7}\right)=.71$ and $I_{C}\left(Q_{8}\right) / I_{C}\left(Q_{7}\right)=.73$.

As indicated by the data of Table VI. 8 c , the variation in low-frequency gain over the range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ for the T 3 design is $15.7 \%$ of the nominal gain, this is substantially lower than the variations for the $T 2$ and T4 designs, but it is much greater than that for the overall feedback configuration, Tl. The total drift in the quiescent output level for the optimum T 3 design is 450 mV over the $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ range.

### 6.3.4 Configuration T4

The design optimization results for the amplifier of Fig. 5.10 are given in Fig. 6.4 and Tables VI. $9 \mathrm{a}, \mathrm{b}$, and c. This amplifier is based on the configuration $T 4$, a series-shunt-series local feedback cascade. The maximum -3 dB bandwidth obtainable fo the T 4 amplifier is 90 MHz , the same as the maximum bandwidth of the series-serics triple configurations, T1.

As indicated in Table VI.9a, all of the collector current in the first stage of the optimum T4 design is supplied through the feedback resistor $R_{f}$; no collector resistor $R_{1}$, is needed. The optimum value of the differential load resistance, $\mathrm{R}_{2}$, on the second stage is the maximum permitted by de conditions. Just as in the $T 2$ amplifier design, the low current in the third stage results in a limited available output voltage swing. For optimum $T 4$ design this swing is $\pm 0.3 \mathrm{~V}$.

TABLE VI.9a
PASSIVE ELEMENT VALUES FOR OPTIMUM T4 DESIGN

$$
\begin{array}{ll}
R_{e 1}=R_{e 2}=50 \Omega & R_{1}=\infty \\
R_{f}=1.1 \mathrm{k} \Omega & R_{2}=2.7 \mathrm{k} \Omega \\
R_{3}=970 \Omega & R_{7}=2.4 \mathrm{k} \Omega \\
C_{f}=0 & R_{8}=4.2 \mathrm{k} \Omega
\end{array}
$$

TABLE VI.9b
DEVICE SPECIFICATIONS FOR OPTIMUM T4 DESIGN

| Device | $n_{e}$ | $n_{b}$ | $\ell_{e}, m i l s$ | $I_{C}, m A$ | $\mathrm{f}_{\mathrm{t}}, \mathrm{MHz}$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{Q}_{1}$ | 2 | 3 | 3.17 | .62 | 245 |
| $\mathrm{Q}_{2}$ | 1 | 1 | .6 | 1.11 | 615 |
| $\mathrm{Q}_{3}$ | 1 | 1 | .80 | .27 | 425 |
|  |  |  |  |  |  |
|  | $\mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{6}\right) / \mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{7}\right)=.56$ |  |  |  |  |
|  | $\mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{8}\right) / \mathrm{I}_{\mathrm{C}}\left(\mathrm{Q}_{7}\right)=.24$ |  |  |  |  |

TABLE VI.9c
TEMPERATURE DEPENDENCE OF GAIN AND DC OUTPUT VOLTAGE FOR T4 DESIGN

| $\mathrm{T},{ }^{\circ} \mathrm{K}$ | $\mathrm{A}_{\mathrm{V}}(0)$ | $\mathrm{V}_{0}, \mathrm{mV}$ |
| :--- | :--- | :--- |
| 218 | 64.71 | +3 |
| 258 | 57.38 | -13 |
| 300 | 50.32 | -36 |
| 348 | 43.66 | -66 |
| 398 | 38.12 | -100 |

Ee.IV adat


| $\infty=1^{\text {g }}$ | $\mathrm{So}^{n}=10 \mathrm{l}$ |
| :---: | :---: |
| $\Omega \times .5=s^{n}$ | 2dI. $1={ }^{\text {H }}$ |
| SAP. $5=r^{\text {a }}$ | SUTO $=\varepsilon^{8}$ |
| $\Omega$ IS. $A=8_{8}$ | $0=3^{3}$ |

mo. ay anay


The optimum device characteristics for the T4 amplifier are given in Table VI.9b. A double emitter, three base contact device, with an emitter stripe length of 3.17 mil , is specified for $Q_{1}$. The optimum structure for $Q_{2}$ is a minimum area device and a single emitter single base contact device with a stripe length of 0.8 mil is optimum for $Q_{3}$. Current ratios in the source transistors are $I_{C}\left(Q_{6}\right) / I_{C}\left(Q_{7}\right)=.56$ and $I_{C}\left(Q_{8}\right) / I_{C}\left(Q_{7}\right)=.24$.

Results of the first-order temperature sensitivity analysis for the optimum T4 design are given in Table VI.9c. The total gain variation over $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ is $53.2 \%$ of the gain at room temperature. This is the highest gain sensitivity obtained for any of the designs considered. It is explained by the fact that the $T 4$ configuration is a cascade of three local feedback loops. The bandwidth is comparable to that of the overall feedback amplifier, Tl, but, as noted in Sec. 6.2.3 the overall feedback results in a much lower gain sensitivity. The total drift in the quiescent output voltage of the T 4 design is 100 mV over $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$. This is comparable to the drift obtained with the Tl configuration.

### 6.4 Comparison of the Optimum Designs

A summary of the performance characteristics for all of the optimum amplifier designs is given in Table VI.10. Included in the table for each design are the -3 dB bandwidth, the input resistance, the maximum available unclipped swing in the output voltage, and the total variations in lowfrequency gain and quiescent output voltage over the temperature range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$. All of the designs have a low-frequency differential voltage gain of 34 dB and quiescent power dissipation of 96 mW .

The data summarized in Table VI. 10 indicates that of, the designs considered, the optimum design based on configuration Pl provides the best

TABLE VI. 10
CIIARACTERISTICS OF OPTIMUM DESIGNS

| Configuration | $\begin{gathered} -3 \mathrm{~dB} \mathrm{BW} \\ (\mathrm{MHz}) \end{gathered}$ | $\begin{gathered} R_{i n} \\ (k \Omega) \end{gathered}$ | $\begin{gathered} \text { Max. }\left\|v_{\text {out }}\right\| \\ \text { (volts) } \end{gathered}$ | Over $\mathrm{T}=-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | ${ }^{\Delta} \mathrm{V}_{\mathrm{V}}(0)$ | $\begin{aligned} & \Delta V_{0} \\ & (m v) \end{aligned}$ |
| P1 | 123 | 850 | 2.4 | .6\% | 30 |
| P2 | 95 | 330 | 2.4 | 2.0\% | 640 |
| P3 | 122 | 17 | 2.4 | 10.2\% | 190 |
| P4 | 105 | 16 | 2.4 | 8.6\% | 160 |
| T1 | 90 | 2,900 | 1.5 | 2.1\% | 100 |
| T2 | 78 | 940 | 0.13 | 38.8\% | 160 |
| T3 | 133 | 26 | 0.9 | 15.7\% | 450 |
| T4 | 90 | 22 | 0.3 | 53.2\% | 100 |

overall performance. The bandwidth for this design is 123 Mllz , second only to the 133 MHz obtained for the T 3 configuration. The input resistance of $850 \mathrm{k} \Omega$ is surpassed only by the $2.9 \mathrm{M} \Omega$ and $940 \mathrm{k} \Omega$ of the Tl and T2 designs. The unclipped output swing for the P1 amplifier is the maximum achieved, $\pm 2.4 \mathrm{~V}$. The $.6 \%$ variation in gain over the temperature range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ is the lowest obtained, as is the 30 mV drift in the quiescent output voltage.

The optimum amplifier designs based on configurations P3 and T3 exhibit bandwidths of 122 MHz and 133 MHz ; only these configurations provide bandwidths comparable to the 123 MHz obtained for the P1 design. However, both the 'P3 and T3 configurations have local series feedback in the input stage and consequently are characterized by the relatively low input resistances of $17 \mathrm{k} \Omega$ and $26 \mathrm{k} \Omega$, respectively. The variation of the 10 w -frequency gain over the temperature range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ is $10.2 \%$ for the P 3 amplifier and $15.7 \%$ for the $T 3$ designs; these values are more than an order of magnitude greater than the $.6 \%$ variation for the optimum Pl design.

Three of the designs included in Table VI. 10 have gain sensitivities to temperature that are substantially lower than those of the other five amplifiers. The anplifier based on the P1 configuration exhibits the smallest variation in gain, $.6 \%$, over the range $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$. The variations for the designs based on the P2 and T1 configurations are $2.0 \%$ and $2.1 \%$, respectively. The distinguishing feature of these three configurations with low gain sensitivity is that all of the common-emitter gain stages are included within a single overall feedback loop. As expected from a consideration of ideal feedback systems, overall feedback results in a significantly greater reduction in gain sensitivity than is achieved with local feedback. Of the three configurations, P1, P2 and Tl, providing a





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$\theta$


1. $\mathrm{g}: \mathrm{ID} \dot{\mathrm{I}} \mathrm{V}$
low gain sensitivity to temperature, the 123 MHz bandwidth of the P1 design is $29 \%$ greater than the 95 Miz obtained for the P2 design and $37 \%$ greater than the 90 MIIz of the Tl amplifier.

The excellent performince obtainable with the Pl configuration is to a large extent, the result of three interrelated factors. First, as for all of the pairs, there are only two gain stages; consequently, the de current level per stage is higher than for the triples and the transistors operate at a higher $f_{T}$. Second, overall feedback is used in the P1 design, resulting in low gain sensitivity and a high input resistance. Finally, an output emitter-follower is included within the overall feedback loop of the Pl configuration, a series-shunt pair. The inclusion of the emitterfollower within the feedback loop reduces the loading of feedback network on the forward amplifier and results in a significant increase in loop gain. This is easily demonstrated by comparing the input resistances, given in Table VI.9, of the P1 and P2 designs; the latter configuration is an overall series-shunt pair cascaded with an emitter follower. The openloop input resistance is higher for the P2 design because of the larger emitter resistor, $\mathrm{R}_{\mathrm{e}}$, in the input stage; however, the closed-10op input resistance is more than a factor of two larger for the Pl configuration. This indicates that the inclusion of the emitter-follower within the feedback loop results in better than a factor of two increase in the loop gain.

The only significant disadvantage of the PI amplifier is that a capacitive feedback element must be used in order to achieve the maximum bandwidth obtainable. The .3 pF for the capacitance is, however, quite small and does not require a large amount of silicon area. Because of the small value needed, it may be feasible to adjust the area of the diffused feedback resistor, $\mathrm{R}_{\mathrm{f}}$ such that compensation can be achieved by connecting the





 2xoteiensit of: bis esiqixt ont xot hall xotyin ei grase xaq fovai fig:




$\qquad$
$\qquad$
arab
16

parasitic capacitance of this resistor as shown in Fig. 6.5. The surrounding $n$ region is connected to the more positive end of the resistor.


Fig. 6.5: Connection of parasitic capacitance for compensation in a feedback network.

## CHAP'TER VII

EXPERIMENTAL RESULTS

### 7.1 Introduction

All of the amplifier designs developed in Chaps. V and VI should be readily integrable in most processing facilities. The configurations do not differ substantially from commonly realized circuits. Nonetheless, in order to verify the feasibility of realizing these configurations, and to confirm the suitability of the device models used in the automated design procedure, both discrete component and monolithic amplifiers have been fabricated.

### 7.2 Discrete Component Realization

The complete amplifier configuration of Fig. 5.3, which is based on a series-series feedback triple, has been realized with discrete components, including matched transistor pairs. The transistors have a typical $\beta_{0}$ of 110 and $f_{T}$ of 425 MHz at a collector current of 1 mA . The discrete realization has been constructed primarily to verify the set up of dc conditions in the amplifier; consequently, the design has not been optimized for the discrete components.

The component values and current levels for the discrete amplifier are given in Table VII.l; the notation is that used in Fig. 5.3. The ratio of currents in the current source transistors $Q_{6}$ and $Q_{7}$ is established with emitter resistors of $250 \Omega$ for $Q_{5}$ and $750 \Omega$ for $Q_{6}$. The dc conditions in the amplifier set up as expected and the specified 34 dB low-frequency gain is achieved. The frequency response of the amplifier

## TABLE VII.I

COMPONF:NT VALUES AND CURRENT
LEVIELS FOR DISCRE:TE AMPLIFIER REALIZATION

| $R_{e 1}=R_{e 2}=200 \Omega$ | $R_{7}=5 \mathrm{k} \Omega$ |
| :--- | :--- |
| $R_{f}=1.2 \mathrm{k} \Omega$ | $R_{8}=1 \mathrm{k} \Omega$ |
| $R_{1}=12 \mathrm{k} \Omega$ | $R_{4}=1.65 \mathrm{k} \Omega$ |
| $R_{2}=10 \mathrm{k} \Omega$ | $R_{5}=3.3 \mathrm{k} \Omega$ |
| $R_{3}=2 \mathrm{k} \Omega$ | $R_{6}=4.7 \mathrm{k} \Omega$ |
|  |  |
| $I_{C}\left(Q_{1}\right)=.5 \mathrm{~mA}$ | $I_{C}\left(Q_{4}\right)=1 \mathrm{~mA}$ |
| $I_{C}\left(Q_{2}\right)=.5 \mathrm{~mA}$. | $I_{C}\left(Q_{5}\right)=1.3 \mathrm{~mA}$ |
| $I_{C}\left(Q_{3}\right)=1 \mathrm{~mA}$ |  |
| $I_{C}\left(Q_{6}\right)$ |  |
| $I_{C}\left(Q_{7}\right)=3$ |  |



Fig. 7.1: Response of discrete component amplifier.
is shown in Fig. 7.1; the -3 dB bandwidth is 34 MHz . Capacitive compensation is not used for the feedback triple. As described in Sec. 5.3.3, compensation is established through a suitable choice of the differential load resistance for the triple.

### 7.3 Monolithic Realization

In addition to the discrete component amplifier, the balanced seriesseries triple portion of the amplifier in. Fig. 5.3 has been fabricated in the Integrated Circuits Laboratory at Berkeley. As noted in Chapter IV, because of optical limitations, the minimum mask dimensions presently achievable in this facility are somewhat larger than those assumed for the designs of Chap. VI. For example, the minimum emitter stripe width is 1.6 mil instead of the .6 mil in Fig. 4.1. The mask dimensions for a minimum area device are illustrated in Fig. 7.2.

To establish a design for monolithic realization, it was necessary to repeat the design optimization procedure for the larger minimum dimensions. These larger dimensional restrictions also preclude realization of the full configuration in Fig. 5.3. However, as indicated in Chap. V, the limitations on the frequency response of the complete amplifier arise entirely from the balanced series-series triple. The configuration of the monolithic amplifier realization is given in Fig. 7.3.

The overall specifications assumed for the amplifier of Fig. 7.3 are a low-frequency differential voltage gain of $37.5 \mathrm{~dB}, \pm 6 \mathrm{~V}$ power supplies, and a quiescent power dissipation of 48 mW . These specifications are equivalent to those used in Chap. V for the complete amplifier of Fig. 5.3. Except for the minimum dimensions, the other constraints in the design optimization procedure are also the same as those used for the


## DIMENSIONS IN MILS

Fig. 7.2: Minimum area device topoloty for monolithic amplifier realization.


Fig. 7.3: Balanced series-series triple configuration.

Fig. 7.3: Balanced series-series triple configuration.


Fig. 7.3: Balanced series-series triple configuration.
amplifier of Fig. S.3. A 1.4 V collector-emitter voltage is specified for $Q_{1}$ and $Q_{2}$, while the assumed quiescent output voltage at the collector of $Q_{3}$ is $3 V$. The emitter resistors, $R_{e 1}$ and $R_{e 2}$, are constrained to be equal for the reasons presented in Sec. 6.1, and the minimum value allowed for a diffused resistor is $50 \Omega$.

The diffusion process used for the monolithic realization is the same as that employed for the device characterization of Chap. IV. This process results in a base diffusion depth of $3.5 \mu \mathrm{~m}$, a base sheet resistance of $125 \Omega /$ square, and a basewidth of $0.8 \mu \mathrm{~m}$. The starting material is a $1 \Omega-\mathrm{cm}$, $10 \mu \mathrm{~m}$ n-type epitaxial layer on a $5 \Omega$ - cm p-type substrate. As is evident from the large value given in Table VII. 3 for $r_{c}^{\prime}$, a buried layer structure was not used.

The results of the design optimization procedure for the amplifier of of Fig. 7.3 are summarized in Tables VII. 2 and VII.3. Given in Table VII. 2 are the passive element values for the optimum design, the optimum dc collector currents for $Q_{1}, Q_{2}$ and $Q_{3}$, and the ratio of quiescent currents in the current source transistors, $Q_{4}$ and $Q_{5}$. The values shown for $R_{1}$ and $R_{2}$ are the maximum allowed by de conditions. The optimum ratio of currents in $Q_{4}$ and $Q_{5}, I_{C}\left(Q_{4}\right) / I_{C}\left(Q_{5}\right)=3.3$, is established by using a minimum area device for $Q_{5}$ and increasing the emitter stripe length of $Q_{4}$.

The optimum planar geometry for the devices $Q_{1}, Q_{2}$ and $Q_{3}$, as indicated by the results of automated design procedure, is the minimum area topology illustrated in Fig. 7.2. Devices with this geometry have been characterized experimentally and the results are summarized in Table VII.3. The devices have a typical $f_{T}$ of 170 MHz at a collector current of 1 mA and collectoremitter voltage of 1.5 V . A constant $\beta_{0}$ of 120 has been assumed because

## TABLE VII. 2

OPTIMUM DESIGN FOR SERIES-SERIES TRIPLE OF FIG. 7.3

$$
\begin{array}{ll}
R_{e 1}=R_{e 2}=210 \Omega & R_{3}=2.06 \mathrm{k} \Omega \\
R_{f}=1.24 \mathrm{k} \Omega & R_{4}=5.8 \mathrm{k} \Omega \\
R_{1}=12.7 \mathrm{k} \Omega & R_{5}=300 \Omega \\
R_{2}=10.0 \mathrm{k} \Omega & \\
I_{C}\left(Q_{1}\right)=.41 \mathrm{~mA} & \\
I_{C}\left(Q_{2}\right)=.46 \mathrm{~mA} & \frac{I_{C}\left(Q_{4}\right)}{I_{C}\left(Q_{5}\right)}=3.3
\end{array}
$$

$$
I_{C}\left(Q_{3}\right)=1.13 \mathrm{~mA}
$$

## TABLE VII. 3

CHARACTERISTICS FOR MINIMUM AREA TRANSISTOR OF FIG. 7.2

$$
\begin{aligned}
& B_{0}=120 \\
& r_{b}^{\prime}=\left(210+\frac{200}{\mathrm{I}_{\mathrm{C}}+1.3}\right) \Omega \text { where } \mathrm{I}_{\mathrm{C}} \text { is in } \mathrm{mA} \text {. } \\
& r_{c}^{\prime}=400 \Omega \\
& \tau_{t}=.22 \mathrm{nsec} \\
& C_{j e}=5.5 \mathrm{pF} \\
& \mathrm{C}_{\mathrm{cb}}=\left\{\begin{array}{l}
1.4 \mathrm{pF} @ \mathrm{~V}_{\mathrm{BC}}=-.7 \mathrm{~V} \\
1.15 \mathrm{pF} @ \mathrm{~V}_{\mathrm{BC}}=-1.6 \mathrm{~V}
\end{array}\right. \\
& C_{\mathrm{cs}}=\left\{\begin{array}{l}
1.25 \mathrm{pF} @ \mathrm{~V}_{\mathrm{SC}}=-6.7 \mathrm{~V} \\
1.23 \mathrm{pF} @ \mathrm{~V}_{\mathrm{SC}}=-7.4 \mathrm{~V} \\
1.16 \mathrm{pF} @ \mathrm{~V}_{\mathrm{SC}}=-9.0 \mathrm{~V}
\end{array}\right.
\end{aligned}
$$

the variation in $\beta_{0}$ over the current range of interest is relatively small.

Given in Table VII. 3 are the values of the total collector-base and collector-substrate capacitances corresponding to the quiescent voltages specified for $Q_{1}, Q_{2}$, and $Q_{3}$. If a . $7 V$ base-emitter voltage is assumed, the reverse bias voltage on the collector-base junction is . 7 V for $R_{1}$, . 7 V for $Q_{2}$, and $1.4 V$ for $Q_{3}$. The collector-substrate reverse voltages are 6.7 V for $Q_{1}, 7.4 \mathrm{~V}$ for $Q_{2}$, and 9 V for $Q_{3}$. For the device models in the design program, these capacitances are divided into two components as described in Sec. 4.3 and Fig. 4.2. As indicated in Sec. 4.3, this division is established from geometrical estimates. For the minimum area device of Fig. 7.2, the components in the model of Fig. 4.2 are given by

$$
\begin{aligned}
& C_{c b 1}=.33 C_{c b} \\
& C_{c b 2}=.67 \mathrm{C}_{\mathrm{cb}} \\
& \mathrm{C}_{\mathrm{cs} 1}=.40 \mathrm{C}_{\mathrm{cs}} \\
& \mathrm{C}_{\mathrm{cs} 2}=.60 \mathrm{C}_{\mathrm{cb}}
\end{aligned}
$$

where $C_{c b}$ and $C_{c s}$ are the total capacitances given Table VII.3.
A photograph of the monolithic balanced triple is shown in Fig. 7.4. The experimental set up for measuring the voltage gain-frequency response of the amplifier is described in Appendix E. Discrete emitter-followers are used to provide a very high impedance load for the monolithic amplifier. The capacitive loading of these emitter-followers, as well as parasitic capacitance associated with the packaging, have been taken into account in the design optimization of the amplifier. The amplifier is


Magnification: 27.5X

Fig. 7.4: Photograph of monolithic balanced triple.
mounted in a TO-5 can with a typical pin-to-header capacitance of .8 pF .
Initial experimental measurements indicated an amplifier response with severe bandedge peaking. It was subsequently discovered that an incorrect value had been used in the design program for the transistor collector-substrate capacitance. The value used was much too low. When the correct value of capacitance was used, a frequency response analysis of the realized design displayed the experimentally observed peaked. Additional analysis runs indicated that the peaking could be eliminated with a 1.8 pF feedback capacitor in shunt across the resistor $\mathrm{R}_{\mathrm{f}}$. Discrete capacitors of this value were added to the experimental amplifier and the expected response shape was obtained.

The measured response for a typical realization, with the compensation capacitors added, is shown in Fig. 7.5. Included in the figure is the theoretically predicted response when the correct collector substrate capacitances and the compensation capacitor are used. The experimental response exhibits the predicted low frequency differential gain of 37.5 dB with a - 3 dB bandwidth of 34 MHz . The bandwidth is within $6 \%$ of the expected value.

The average of the differential offset voltage measured for several units is 2.5 mV referred to the input. This value is typical for differential amplifiers with a bipolar transistor input transistor pair.

Fig. 7.5: Response of monolithic amplifier.

## CHAPTER VIII

CONCLUSION

An effective program has been diveloped for the automated design of monolithic broadband amplifiers. This program utilizes most of the available degrees of design freedom to achieve optimum amplifier performance. For a given configuration, dc conditions, device geometry, and all passive elements are adjusted to obtain the maximum -3 dB bandwidth consistent with a specified gain and quiescent power dissipation.

In this study, the design program has been used to examine a particular class of monolithic amplifiers. This class is defined by the requirements for a dc-coupled voltage gain response with a large bandwidth, restricted quiescent power dissipation, low gain sensitivity to temperature and processing, and zero volt quiescent levels at input and output. The latter specification permits the direct cascading of amplifiers without coupling elements.

Complete differential amplifiers suitable for meeting the specified requirements have been developed from eight basic feedback configurations. The automated design program has been used to optimize each of these amplifiers under the specifications for a voltage gain of 34 dB and a power dissipation of 96 mW . The results of the design optimization procedure have then been used to establish the relative effectiveness of the basic feedback configurations.

Of the basic configurations considered, the series-shunt feedback pair with an output emitter-follower included in the feedback loop provides
the best overall performance. The amplifier based on this configuration achieves a relatively large bandwidth, very low gain and dc output level sensitivities, a high input resistance, and a large available output voltage swing. As for all of the designs considered, the bandwidth is limited by the restricted power dissipation.

The comparison of basic configurations presented in this study differs significantly from the results of previous work [53]. The earlier work was based on computer-aided analysis, and a trial and error approach was used to establish designs for various feedback configurations. Arbitrary choices were made for dc conditions and device geometry. A comparison of the final designs arrived at in this preliminary work indicated that the series-series feedback triple provided performance superior to that of the series-shunt pair. However, the emitter-follower was not included within the feedback loop of the pair and, also, it was not possible to establish the best possible performance for each of the configurations.

The amplifier bandwidths achieved in this report using automated design optimization are typically a factor of two greater than those of similar commercial designs with comparable transistor $f_{T}$ 's. In a given design situation, the improvement obtainable with automated design relative to nonautomated results depends on two factors. The first is the influence on the response of parameters, such as dc conditions, that are fixed in a nonautomated procedure. The second is whether or not a fortunate choice is made for these fixed parameters on a nonautomated basis.

At least as significant as the improved performance obtainable with an automated design procedure is the capability to document the existence of a design optimum. As noted above, conclusions with regard to the relative effectiveness of alternative design approaches may depend
significantly on whether or not the best possible performance is obtained for each approach. Once the automated design procedure is completed successfully for an amplifier, no further improvement can be obtained under the constraints assumed in the procedure.

The design approach described in this dissertation is based on relatively new techniques that have not heretofore been applied to practical design problems. The principal results of this work are a demonstration of the effectiveness of these techniques, as well as an indication of their potential for application to a much broader class of circuit design problems. While in this study consideration has been given to a very specific class of circuits, the approach is readily extended to more general circuit design work.

There are, of course, significant problems yet to be considered if automated design is to become a reality for a large class of circuits. For example, the choice of a performance index is critical in a fully automated design procedure. The effectiveness and efficiency of the procedure depends in large part on establishing a suitable index. Even for the work presented in this report, it is not clear that the least squared error formulation that has been used is the most effective index for achieving a near maximally flat frequency response with maximum -3 dB bandwidth.

The choice of optimization algorithm is also critical in determining the efficiency of an automated design procedure. The Fletcher-Powell algorithm has been used here because of its successful applications in other fields. For circuit design, however, some other search formulation may well be more effective.

A general concern of automated circuit design procedures is the existance of local minima. In any numerical search procedure, there are
no direct means for determining whether or not a minimum is global. The only solution to this problem is to attempt to locate all of the minima in the space of allowable design parameters by conducting numerous searches starting at different initial designs. Fortunately, for the designs considered in this case only a single physically realistic optimum has been found in each case. Apparently, the restriction to physically realizable designs does much to allieviate the local minima problem.

## APPENDIX A

THE ADJOINT NETWORK

The development of the adjoint network concept for evaluating network response sensitivities has been described for the general case by Director and Rohrer [21-23]. In this appendix, the development is presented for the restricted case of a two-port network with a single current source excitation; consideration is restricted to a frequency domain response formulation and to networks with only conductance (G), capacitance (C), and transconductance $\left(g_{m}\right)$ elements.

Consider the linear, time invariant two-port network $\eta$, shown in Fig. A.1, that is comprised of G, C and $g_{m}$ elements, with the current source excitation $I_{S}(j \omega)$ and the open-circuit voltage response $V_{0}(j \omega)$. The intent of following formulation is to establish the sensitivity of $V_{0}(j \omega)$ to any element, $P$, of the network under a given excitation.

Let $\hat{\eta}$ represent a network that is topologically equivalent to $\eta$, but for which the branch relations are as yet defined. Let the branch current and voltage responses in $\eta$ be denoted by $I_{B}(j \omega)$ and $V_{B}(j \omega)$ and those in $\hat{\eta}$ be denoted by $\psi_{B}(j \omega)$ and $\phi_{B}(j \omega)$. Then, by Tellegen's theorem [54]

$$
\begin{align*}
& \sum_{B} v_{B}(j \omega) \phi_{B}(j \omega)=0  \tag{A.la}\\
& \sum_{B} \psi_{B}(j \omega) I_{B}(j \omega)=0 \tag{A.1b}
\end{align*}
$$



Fig. A.l: Linear, time-invariant two-port network with current source excitation and open circuit output.


Fig. A.2: Representation of a voltage controlled current source in $\geqslant$.
where the summation is carried out over all branches, including the current source, the open circuit output branch, and the open circuit that is associated with the input of any transconductances, as indicated in Fig. A.2. If the elements of $\eta$ are perturbed, the responses in the network are altered. Nonetheless, the relationship (A.1) between $\geqslant$ and $\hat{\eta}$ arising from Tellegen's theorem is not changed as long as the topology of $\eta$ is not modified. That is, if $\Delta V_{B}(j \omega)$ and $\Delta I_{B}(j \omega)$ represent the changes in the responses of $\eta$ due to perturbations in the network elements,

$$
\begin{align*}
& \sum_{B}\left[V_{B}(j \omega)+\Delta V_{B}(j \omega)\right] \phi_{B}(j \omega)=0  \tag{A.2a}\\
& \sum_{B} \psi_{B}(j \omega)\left[I_{B}(j \omega)+\Delta I_{B}(j \omega)\right]=0 \tag{A.2b}
\end{align*}
$$

Subtracting (A.1a) from (A.2a) and (A.1b) from (A.2b) yields

$$
\begin{align*}
& \sum_{B} \Delta V_{B}(j \omega) \phi_{B}(j \omega)=0  \tag{A.3a}\\
& \sum_{B} \psi_{B}(j \omega) \Delta I_{B}(j \omega)=0 \tag{A.3b}
\end{align*}
$$

and subtracting (A.3b) from (A.3a) results in

$$
\begin{equation*}
\sum_{B}\left[\Delta V_{B}(j \omega) \phi_{B}(j \omega)-\Delta I_{B}(j \omega) \psi_{B}(j \omega)\right]=0 \tag{A.4}
\end{equation*}
$$

The summation of (A.4) may be broken into branch types and expressed as

$$
\begin{align*}
{\left[\Delta \mathrm{V}_{\mathrm{S}} \phi_{\mathrm{S}}-\Delta \mathrm{I}_{\mathrm{S}} \Psi_{\mathrm{S}}\right]+\left[\Delta \mathrm{V}_{0} \phi_{0}-\Delta \mathrm{I}_{0} \psi_{0}\right] } & +\sum_{\mathrm{G}}\left[\Delta \mathrm{~V}_{\mathrm{G}} \phi_{\mathrm{G}}-\Delta \mathrm{I}_{\mathrm{G}} \psi_{\mathrm{G}}\right] \\
& +\sum_{\mathrm{C}}\left[\Delta \mathrm{~V}_{\mathrm{C}} \phi_{\mathrm{C}}-\Delta \mathrm{I}_{\mathrm{C}} \psi_{\mathrm{C}}\right] \\
& +\sum_{\mathrm{VCI}}\left[\Delta \mathrm{~V}_{\mathrm{VCI}} \phi_{\mathrm{VCI}}-\Delta \mathrm{I}_{\mathrm{VCI}} \psi_{\mathrm{VCI}}\right] \\
& +\sum_{\mathrm{VDI}}\left[\Delta \mathrm{~V}_{\mathrm{VDI}} \phi_{\mathrm{VDI}}-\Delta \mathrm{I}_{\mathrm{VDI}} \psi_{\mathrm{VDI}}\right]=0 \tag{A.5}
\end{align*}
$$

where the parenthetical inclusion of $j \omega$ has been dropped from the frequency domain notation, as is done in the remainder of this appendix. In the representation (A.5), transconductances are regarded as two branch elements as shown in Fig. A.2. The open-circuit controlling branch is denoted by the subscript VCI and the dependent current source branch by the subscript VDI.

The next step is to introduce the branch relationships of $\eta$ into (A.5) and define the branch relations for $\hat{\eta}$. The branch relationships for the conductance branches of $\eta$ are of the form

$$
\begin{equation*}
\mathrm{I}_{\mathrm{G}}=\mathrm{GV}_{\mathrm{G}} \tag{A.6}
\end{equation*}
$$

If the conductance is perturbed by $\Delta G$, then

$$
\begin{equation*}
\left(\mathrm{I}_{\mathrm{G}}+\Delta \mathrm{I}_{\mathrm{G}}\right)=(\mathrm{G}+\Delta \mathrm{G})\left(\mathrm{V}_{\mathrm{G}}+\Delta \mathrm{V}_{\mathrm{G}}\right) \tag{A.7}
\end{equation*}
$$

If the second-order term is neglected and (A.6) is introduced into (A.7),

$$
\begin{equation*}
\Delta I_{G}=G \Delta V_{G}+V_{G} \Delta_{G} \tag{A.8}
\end{equation*}
$$

The summation in (A.5) corresponding to the conductance branches may then be expressed as

$$
\begin{equation*}
\sum_{G}\left[\left(\phi_{G}-G \psi_{G}\right) \Delta v_{G}-V_{G} \psi_{G} \Delta G\right] \tag{A.9}
\end{equation*}
$$

Similarly, for the capacitance branches

$$
\begin{equation*}
I_{C}=j \omega C V_{C} \tag{A.10}
\end{equation*}
$$

and if $C$ is perturbed by $\Delta C$ then

$$
\begin{equation*}
\Delta I_{C}=j \omega C \Delta V_{C}+j \omega V_{C} \Delta C \tag{A.11}
\end{equation*}
$$

where the second-order term is neglected. If (A.11) is introduced into the capacitance-branch summation of (A.5), the summation becomes

$$
\begin{equation*}
\sum_{C}\left[\left(\phi_{C}-j \omega C \psi_{C}\right) \Delta V_{C}-j \omega V_{C} \psi_{C} \Delta C\right] \tag{A.12}
\end{equation*}
$$

The branch relationships for the voltage dependent current source shown in Fig. A.l are

$$
\begin{align*}
& \mathrm{I}_{\mathrm{VCI}} \equiv 0  \tag{A.13a}\\
& \mathrm{I}_{\mathrm{VDI}}=\mathrm{g}_{\mathrm{m}} \mathrm{~V}_{\mathrm{VCI}} \tag{A.13b}
\end{align*}
$$

If $g_{m}$ is perturbed and second-order terms are neglected,

$$
\begin{align*}
& \Delta \mathrm{I}_{\mathrm{VCI}}=0  \tag{A.14a}\\
& \Delta \mathrm{I}_{\mathrm{VDI}}=\mathrm{g}_{\mathrm{m}} \Delta \mathrm{~V}_{\mathrm{VCI}}+\mathrm{V}_{\mathrm{VCI}} \Delta \mathrm{~g}_{\mathrm{m}} \tag{A.14b}
\end{align*}
$$

The sumnation in (A.5) corresponding to the controlling and controlled branches of voltage dependent current sources may be combined and expressed as

$$
\begin{equation*}
\sum_{g_{\mathrm{m}}}\left[\phi_{\mathrm{VCI}} \Delta \mathrm{~V}_{\mathrm{VCI}}+\left(\phi_{\mathrm{VDI}}-\mathrm{g}_{\mathrm{m}} \psi_{\mathrm{VDI}}\right) \Delta \mathrm{V}_{\mathrm{VDI}}-\mathrm{V}_{\mathrm{VCI}} \psi_{\mathrm{VDI}} \Delta g_{\mathrm{m}}\right]=0 \tag{A.15}
\end{equation*}
$$

For the current source branch in (A.5)

$$
\begin{equation*}
\Delta I_{S}=0 \tag{A.16}
\end{equation*}
$$

while for the output branch

$$
\begin{equation*}
I_{0} \equiv 0 \tag{A.17}
\end{equation*}
$$

and hence

$$
\begin{equation*}
\Delta I_{0}=0 \tag{A.18}
\end{equation*}
$$

The first two terms in (A.5) may therefore be reduced to

$$
\begin{equation*}
\Delta V_{S} \phi_{S}+\Delta V_{0} \phi_{0} \tag{A.19}
\end{equation*}
$$

In order to arrive at a formulation of the response sensitivity for $\mathscr{N}$ it is necessary to elimate the dependence of (A.9) on $\Delta V_{G}$, (A.12) on $\Delta V_{C}$, and (A.15) on $\Delta V_{V C I}$ and $\Delta V_{V D I}$. This can be accomplished by defining the following branch relations for the network $\hat{n}$

$$
\begin{align*}
& \phi_{G}=G \psi_{G}  \tag{A.20}\\
& \phi_{C}=j \omega C \psi_{C} \tag{A.21}
\end{align*}
$$

and

$$
\begin{align*}
\phi_{\mathrm{VCI}} & =0  \tag{A.22a}\\
&  \tag{A.22b}\\
\phi_{\mathrm{VDI}} & =\mathrm{g}_{\mathrm{m}} \psi_{\mathrm{VDI}}
\end{align*}
$$

The network $\hat{\gamma 2}$ with the branch relations defined by (A.20) - (A.22) is referred to as the linear adjoint network corresponding to the original network, $\geqslant$. The relationships (A.20) and (A.21) indicate that conductance and capacitance branches in $\eta$ correspond to identical branches in $\hat{n}$. The expressions (A.22) characterize the voltage controlled current source in $\hat{\eta}$ shown in Fig. A.3. The roles of the controlling and controlled branches are reversed from those in the original network $\sim$.

If branch relations for $\hat{n}$ are defined by equations (A.20) - (A.22) and (A.9), (A.12), (A.15) and (A.19) are used in (A.5),

$$
\begin{equation*}
\Delta \mathrm{V}_{\mathrm{S}} \phi_{\mathrm{S}}+\Delta \mathrm{V}_{0} \phi_{0}=\sum_{\mathrm{G}} \mathrm{~V}_{\mathrm{G}} \psi_{\mathrm{G}} \Delta \mathrm{G}+\sum_{\mathrm{C}} j \omega \mathrm{~V}_{\mathrm{C}} \psi_{\mathrm{C}} \Delta \mathrm{C}+\sum_{\mathrm{g}_{\mathrm{m}}} \mathrm{~V}_{\mathrm{VCI}} \psi_{\mathrm{VDI}} \Delta g_{\mathrm{m}} \tag{A.23}
\end{equation*}
$$

In to determine the sensitivity of $\mathrm{V}_{0}$ directly, the following excitations are applied to the adjoint network.

$$
\begin{align*}
& \phi_{S}=0  \tag{A.24a}\\
& \phi_{0}=1 \tag{A.24b}
\end{align*}
$$

as indicated in Fig. A.4. Note the direction of the independent source $\phi_{0}$ in the figure; consistent branch voltage and current definitions are followed for all branches.

When the excitations of (A.24) are applied, then (A.23) may be


Fig. A. 3: Voltage controlled current source in $\hat{\eta}$ corresponding to the voltage controlled current source of $\eta$ shown in Fig. A. 2 .


Fig. A.4: Linear adjoint network $\hat{n}$, corresponding to network $\geqslant$.
expressed as

$$
\begin{equation*}
\Delta V_{0}=\underset{\sim}{\mathcal{V}^{t}} \underset{\sim}{p} \tag{A.25}
\end{equation*}
$$

where $\Delta P$ is a column vector of the network elements and $\underset{\sim}{\mathcal{I}}$ is a column vector of sensitivity components, $\frac{\partial V_{0}}{\partial P}$. The corresponding components of $\Delta \underset{\sim}{\mathrm{P}}$ and $\underset{\sim}{\underset{\sim}{e}}{ }^{\mathrm{t}}$ are given in Table A.l. The sensitivity component for a conductance branch is the product of branch voltages in the original and adjoint networks; for a capacitance branch it is the product of branch voltages multiplied by $j \omega$. For the voltage controlled current sources the sensitivity component is the product of controlling branch voltages $n$ and $\hat{n}$.

In the limit as $\Delta \mathrm{P} \rightarrow 0$, (A.25) may be expressed as

$$
\begin{equation*}
\nabla_{\mathrm{p}} \mathrm{v}_{0}=\underset{\sim}{\mathcal{M}} \tag{A.26}
\end{equation*}
$$

Thus $\underset{\sim}{y}$ is simply the gradient of the response $V_{0}$ with respect to the network elements of $\eta$.

TABLE A. 1

| $\Delta P_{i}$ | $\frac{\partial V_{0}}{\partial P_{i}}$ |
| :---: | :---: |
| $\Delta G$ | $V_{G} \Psi_{G}$ |
| $\Delta C$ | $j \omega V_{C} \Psi_{C}$ |
| $\Delta g_{m}$ | $V_{V C I} \psi_{V D I}$ |

## APPENDIX B

## TIIE FLETCHER-PONELL ALGORITHM

When the gradients of a performance index are relatively easy to obtain, as in the case where the adjoint network approach is used, the algorithm of Fletcher and Powell is regarded as one of the most effective approaches for finding the minimum of the index. This algorithm is based on a procedure introduced by Davidson [55], and it is well described in the original article by Fletcher and Powell [56]. In this appendix, a brief summary of the algorithm is given.

In the following equations the notation $\underset{\sim}{x}$ is used to represent the column vector of $n$ independent variables

$$
\underset{\sim}{x}=\left[\begin{array}{c}
x^{1}  \tag{B.1}\\
x^{2} \\
\vdots \\
x^{n}
\end{array}\right]
$$

and the notation for the corresponding row vector is $\underset{\sim}{x}$. The scalar objective function of the variables represented by $\underset{\sim}{x}$ is expressed as $f$ and the vector $\underset{\sim}{g}$ is the gradient of $f$ with respect to $\underset{\sim}{x}$.

The development of the algorithm for minimizing $f$ is based on assuming an ideal quadratic form for this function.

$$
\begin{equation*}
f=f_{0}+\underset{\sim}{a}{ }_{\sim}^{t} \underset{\sim}{x}+\frac{1}{2} \underset{\sim}{x}{ }^{t} \underset{\sim}{x} \tag{B.2}
\end{equation*}
$$

where $G$ is a positive definite $n \times n$ nonsingular matrix. For the case where
the objective function is quadratic, the method of Fletcher and Powell guarantees convergence to the minimum in $n+1$ iterations. For the more practical case where $f$ is not quadratic; convergence takes longer and cannot be guaranteed. llowever, in the neighborhood of the minimum the objective function is usually well approximated by a quadratic form; when the search reaches this neighborhood, the algorithm rapidly converges to the minimum.

If $\underset{\sim}{x}$ * denotes the point corresponding to the minimum of $f$, the step needed to reach $\underset{\sim}{x}{ }^{*}$ from any point $\underset{\sim}{x}$ is given by

$$
\begin{equation*}
{\underset{\sim}{x}}^{*}-\underset{\sim}{x}=-G^{-1} \underset{\sim}{g} \tag{B.3}
\end{equation*}
$$

The gradient $g$, but not the matrix of second order derivatives $G$, is assumed to be computationally available. The form of (B.4) suggests, however, that a search direction other than that of steepest descent (the negative gradient direction) be used. Hence a positive definite matrix $H$ is substituted for $G^{-1}$ in the iterative search procedure. The initial choice of $H$ is arbitrary, but $H$ is modified as the search proceeds to better approximate $G^{-1}$ : Upon convergence of the search to the minimum, H converges to $\mathrm{G}^{-1}$; thus, the algorithm not only locates the minimum but provides curvature information valuable for testing convergence.

At the $i^{\text {th }}$ iteration, the starting point is denoted by $\underset{\sim}{x}$, with the corresponding gradient ${\underset{\sim}{g}}^{i}$ and matrix $H_{i}$. Let $\underset{\sim}{s}$ denote the direction of search from $\underset{\sim}{x}{ }_{i}$. The initial choice for the matrix $H$ is often the unit matrix

$$
H_{1}=I \triangleq\left(\begin{array}{cccccc}
1 & 0 & 0 & . & . &  \tag{B.4}\\
0 & 1 & 0 & . & & 0 \\
0 & 0 & & & & \\
\hline
\end{array}\right)
$$

and the search consequently begins in the direction of steepest descent, $-\mathrm{g}_{1}$. The iterative procedure at the $\mathrm{i}^{\text {th }}$ iteration is as follows:

1. Choose the search direction

$$
\begin{equation*}
{\underset{\sim}{\mathbf{s}}}=-\mathrm{H}_{\mathbf{i}}{\underset{\sim}{i}}_{\mathbf{i}} \tag{B.5}
\end{equation*}
$$

2. Find the scalar $\alpha_{i}>0$ such that $f\left({\underset{\sim}{x}}^{x}+\alpha_{i} \mathbf{s}_{i}\right)$ is a minimum with respect to $\lambda$ along the line

$$
\begin{equation*}
\underset{\sim}{x}=\underset{\sim}{x} i \tag{B.6}
\end{equation*}
$$

3. Let

$$
\begin{equation*}
\underset{\sim}{\Delta x}=\alpha_{i} \mathbf{s}_{\sim}^{i} \tag{B.7}
\end{equation*}
$$

4. Then the starting point for the next iteration is given by

$$
\begin{equation*}
\underset{\sim}{x_{i}+1}=\underset{\sim}{x} i+\underset{\sim}{x} \underset{i}{x} \tag{B.8}
\end{equation*}
$$

5. Evaluate $\underset{\sim}{f(\underset{i+1}{x})}$ and $\underset{\sim}{g_{i+1}}$. Note that $\underset{\sim}{g}{ }_{i+1}$ is orthogonal to $\underset{\sim}{\Delta x}$,

$$
\begin{equation*}
\Delta x_{i}^{t} g_{i+1}=0 \tag{B.9}
\end{equation*}
$$





6. To update the matrix $\mathrm{H}_{\mathrm{i}}$, let

$$
\begin{equation*}
\Delta{\underset{\sim}{i}}_{i}={\underset{\sim}{g}+1}-{\underset{\sim}{g}}_{i} \tag{B.10}
\end{equation*}
$$

7. Then

$$
\begin{equation*}
H_{i+1}=H_{i}+A_{i}+B_{i} \tag{B.11}
\end{equation*}
$$

where

$$
\begin{equation*}
A_{i}=\frac{\Delta{\underset{\sim}{x}} \quad \Delta{\underset{\sim}{x}}_{t}^{t}}{\underset{\sim}{x} \underset{\sim}{t} \Delta{\underset{\sim}{g}}_{i}^{t}} \tag{B.12}
\end{equation*}
$$

and

$$
\begin{equation*}
B_{i}=-\frac{H_{i} \Delta{\underset{\sim}{g}}_{i} \Delta{\underset{\sim}{i}}_{i}^{t} H_{i}}{\Delta{\underset{\sim}{g}}_{i}^{t} H_{i} \Delta{\underset{\sim}{g}}_{i}} \tag{B.13}
\end{equation*}
$$

Fletcher and Powell have proven both the stability and convergence properties of this algorithm for quadratic functions and have demonstrated that the matrices $H_{i}$ converge to $G^{-1}$ as $\underset{\sim}{x}$ converges to the optimum $\underset{\sim}{x}$.

In an appendix to their article, Fletcher and Powell suggest that the use of cubic interpolation to locate the directional minimums, that is, to define $\alpha_{i}$ at each iteration. To form this interpolation the minimum must first be bounded; this is accomplished by first finding a point ${\underset{\sim}{\mathbf{z}}}_{\mathbf{i}}$ along the line $\underset{\sim}{x}=\underset{\sim}{x} i+\lambda{\underset{\sim}{i}}$ with $\lambda>0$ such that the directional derivative has changed sign from negative to positive. If $\underset{\sim}{g} \underset{z}{g}$ is the gradient at $\underset{\sim}{\mathbf{z}}$

$$
\begin{equation*}
{\underset{\sim}{\underset{z}{2}}}_{t}^{s_{i}}>0 \tag{B.14}
\end{equation*}
$$

whereas, if $\underset{\sim}{g}$ denotes the gradient at $\underset{\sim}{x}(\underset{\sim}{x} \underset{\sim}{g} \underset{\sim}{g})$,

$$
\begin{equation*}
g_{x}^{t} \underset{\sim}{s} \underset{i}{s}<0 \tag{B.15}
\end{equation*}
$$

If $f_{x}$ and $f_{z}$ denote the function values at the points $\underset{\sim}{x}$ and $\underset{\sim}{z}$, then $\alpha_{i}$ can be estimated with a cubic interpolation using $f_{x}, f_{y}$ and the gradient components (directional derivatives) along $\underset{\sim}{s}$ :
where $\lambda_{i}$ is the scalar step corresponding to the point $\underset{\sim}{z}{ }_{i}$,

$$
\begin{equation*}
\underset{\sim}{z} \underset{i}{ }=\underset{\sim}{x} i+\lambda_{i} \underset{\sim}{s} \mathbf{i} \tag{B.17}
\end{equation*}
$$

and

$$
\begin{align*}
& \gamma \triangleq \frac{3}{\lambda_{i}}\left(f_{x}-f_{y}\right)+\underset{\sim}{g} \underset{\sim}{t} \underset{\sim}{s}+{\underset{\sim}{y}}_{t}^{\sim}{\underset{\sim}{i}}  \tag{B.18}\\
& w \triangleq\left[z^{2}-\left(g_{x}^{t} \underset{\sim i}{s}\right)(\underset{\sim}{y} \underset{\sim i}{s})\right]^{1 / 2} \tag{B.19}
\end{align*}
$$

In the program ADOP, the point $\underset{\sim}{z} \mathbf{i}$ is located by first choosing $\lambda$ such that

$$
\lambda=\text { minimum of }\left\{\phi, \frac{-2\left(f_{x}-\hat{f}\right)}{{\underset{\sim}{x}}_{\mathrm{x}}^{\mathrm{t}} \underset{\sim i}{s}}\right\}
$$

where $\hat{f}$ is an estimated lower bound for $f$ and $\phi$ is the step such that the maximum change in any component of $\underset{\sim}{x}$ is $25^{\circ}$ of its value at $\underset{\sim}{x}$. If the first step does not bound a minimum, an additional step is taken. Thereafter, the step size is doubled until the minimum is bounded. When several steps are necessary, $\underset{\sim}{\mathbf{x}}$ is changed so that the minimum is bounded by the smallest possible interval among the points examined along $\underset{\sim}{s}$.

Equations (B.14) and (B.15) represent the conditions needed to bound a directional minimum.

Once interpolation is used, the estimate of the minimum must be checked by determinating whether or not $f\left(\underset{\sim}{x}{ }_{i}+\alpha_{i}{\underset{\sim}{s}}^{i}\right)$ is less than $f_{x}$ and $f_{y}$. If not the interpolation is repeated over a smaller interval
 Which interval is used is determined from the directional derivative at the test point.








## APPENDIX C

## MEASUREMENT OF BASE RESISTANCE

The empirical characterization of $r_{b}^{\prime}$ given in Chapt. IV is based on measurements of transistor input impedance at high frequencies. The basic assumption of the method is that the input impedance may be modeled by the RC network shown, in Fig. C.l. The input impedance of this circuit is given by

$$
\begin{equation*}
z_{i n}(j \omega)=\left(r_{b}^{\prime}+r_{\pi}\right) \frac{l+j \omega\left(r_{b}^{\prime} \| r_{\pi}\right) C_{t}}{1+j \omega r_{\pi} C_{t}} \tag{C.1}
\end{equation*}
$$

A plot of the real vs. imaginary parts of (C.1) as a function of frequency results in the circular locus shown in Fig. C.2, with intercepts on the real axis of $r_{b}^{\prime}+r_{\pi}$ at $\omega=0$ and $r_{b}^{\prime}$ at $\omega=\infty$.

To determine $r_{b}^{\prime}$, the real and imaginary parts of the input impedance are measured for several frequency points in a range where they lie on a circular locus. There are usually deviations from the circle at very high frequencies. Once the circular locus is established, $r_{b}^{\prime}$ is easily estimated by extrapolating the measurements to the $\omega=\infty$ intercept of the real axis. The bandedge of the amplifiers of interest generally lies in or near the range of frequencies where the experimental points lie on the circle. Thus, this form of measurement leads to an estimate of $r_{b}^{\prime}$ appropriate to the bandedge response. It is in this region of the response where $r_{b}^{\prime}$ has its most significant effect on the amplifiers considered in this study.

## 









$\qquad$ rem : \%
$\qquad$
$\qquad$
$\qquad$
-




Fig. C.1: Circuit model for transistor input impedance.


An example of the measurement $r_{b}^{\prime}$ for a typical device is illustrated in Fig. C.3. The input impedance is obtained from measurements of the equivalent shunt input conductance, $G_{p}$, and capacitance, $C_{p}$, made with a Wayne-Kerr VHF Admittance Bridge, Model B801. The experimental setup is illustrated in Fig. C.4. From the equivalent $G_{p}$ and $C_{p}$ at a frequency $\Omega$, the real and imaginary parts of the input impedance are given by

$$
\begin{align*}
& \operatorname{Re}\left[z_{i n}(j \omega)\right]=\frac{G_{p}(\omega)}{\left[G_{p}(\omega)^{2}+\omega^{2} C_{p}(\omega)^{2}\right]}  \tag{C.2}\\
& \operatorname{Im}\left[z_{i n}(j \omega)\right]=\frac{-\omega C_{p}(\omega)}{\left[G_{p}(\omega)^{2}+\omega^{2} C_{p}(\omega)^{2}\right]} \tag{C.3}
\end{align*}
$$



Fig. C.3: Measured data for determining $r_{b}^{\prime}$ in a typical device.

Fig. C.4: Experimental set up for deterinining $r_{b}^{\prime}$.

## APPENDIX D

DC OUTPUT LEVEL SENSITIVITY

The common-mode equivalent half circuit of Fig. D.l can be used to show that the current source biasing in the amplifiers of Figs. 5.3 and 5.6 desensitizes the quiescent output collector voltage for the basic feedback amplifiers. For the series-series triple of Fig. $2, I_{3}=I_{f}$, and, neglecting base currents, the de voltage, $\mathrm{V}_{\mathrm{C} 3}$, may be expressed as

$$
\begin{equation*}
V_{C 3}=v_{C C}+\frac{V_{C C}+V_{E E}-\left(\phi_{2}+\phi_{4}\right)-\left(\frac{R_{1}}{R_{2}}+2 \frac{R_{B}}{R_{2}}\right)\left(V_{C C}+\phi_{1}-\phi_{2}\right)}{\frac{R_{f}}{R_{3}}\left(\frac{R_{1}}{R_{1}}+2 \frac{R_{2}}{R_{2}}\right)+\frac{1}{R_{3}}} \tag{D.1}
\end{equation*}
$$

where $\gamma=I_{C}\left(\phi_{4}\right) / I_{C}\left(\phi_{5}\right)$. If the supple voltages and resistor ratios in (D.1) are assumed to be temperature insensitive, and if $\phi \triangleq \phi_{1} \approx \phi_{2} \approx \phi_{3} \approx \phi_{4}$, then the temperature dependence of $\mathrm{V}_{\mathrm{C} 3}$ is given approximately by:

$$
\begin{equation*}
\frac{\partial V_{C 3}}{\partial T} \approx-\frac{2}{\frac{R_{f}}{R_{3}}\left(\gamma_{\frac{1}{R_{2}}}^{R_{2}}+\frac{R_{B}}{R_{2}}\right)+\frac{R_{1}}{R_{3}}} \frac{\partial \phi}{\partial T} \tag{D.2}
\end{equation*}
$$

For the data of Tables VI. $6 a$ and $b$,

$$
\begin{equation*}
\frac{\partial \mathrm{V}_{\mathrm{C} 3}}{\partial \mathrm{~T}} \approx-.23 \frac{\partial \phi}{\partial \mathrm{~T}} \tag{D.3}
\end{equation*}
$$

Thus, the change in $\mathrm{V}_{\mathrm{C} 3}$ with temperature corresponds to approximately $25 \%$


Fig. D.1: Common-mode half circuit for the basic amplifiers of Figs. 5.3 and 5.6.
of the change in a single base-emitter drop.
The voltage $V_{C 2}$ in Fig. 11 corresponds to the quiescent voltage at the collector of the second stage of the feedback pair in Fig. 7. Independent of the current in $Q_{3}$, this voltage is given by

$$
\begin{equation*}
V_{C 2}=v_{C C}-\frac{v_{C C}+v_{E E}-\left(\phi_{2}+\phi_{4}\right)+\frac{R_{1}}{R_{f}}\left(v_{C C}+\phi_{1}-\phi_{3}\right)}{2 \frac{R_{B}}{R_{2}}+\frac{R_{2}}{R_{f}}+\gamma} \tag{D.4}
\end{equation*}
$$

Under the same assumptions as used for (D.2),

$$
\begin{equation*}
\frac{\partial V_{C 2}}{\partial T} \approx-\frac{2}{2 \frac{R_{B}}{R_{2}}+\frac{R_{2}}{R_{f}}+\gamma} \frac{\partial \phi}{\partial T} \tag{D.5}
\end{equation*}
$$

For the data of Tables VI. $2 a$ and $b$,

$$
\begin{equation*}
\frac{\partial V_{\mathrm{C} 2}}{\partial \mathrm{~T}} \approx-.32 \frac{\partial \phi}{\partial \mathrm{~T}} \tag{D.6}
\end{equation*}
$$

## APPENDIX E <br> MEASUREMIENT OF AMPLIFIER FREQULNCY RESPONSE

A schematic of the experimental set up used to measure the frequency response of the monolithic realizations is shown in Fig. E.l. The emitterfollowers $Q_{1}$ and $Q_{2}$ are used to provide low capacitance ( $<1 p F$ ) probes of the amplifier outputs. The amplifier is packaged in a 12 pin T05 can and mounted in a corresponding AUGET socket. The emitter-followers are mounted as close to the output pins as possible and the inputs are brought in through $50 \Omega$ coaxial cable. The entire configuration is mounted on copper-clad board used as a ground plane.


Fig. E.1: Experimental setup for determining the gain-frequency response of the monolithic amplifier realizations.

## APPENDIX F <br> DESCRIPTION OF DESIGN PROGRAM ADOP

The program ADOP is organized according to the flow chart shown in Fig. F.l. The subroutines in ADOP are described below.

Main Program ADOP:

1. Sets up labelled common.
2. Specifications and frequency range are entered in a data statement.
3. Reads independent variables.
4. Initializes circuit excitation.
5. Initializes tolerances for subroutine FMFP.
6. Calls the search subroutine FMFP.
7. Prints returned values of independent variables upon completion of search by FMFP.

Subroutine FMFP:
This subroutine directs the search for the minimum of the performance index. It is based on the Fletcher-Powell algorithm described in Appendix B. The routine used is an extensive modification of that available in the IBM Scientific Subroutine Package/System 360. In conducting the search for the independent variables that minimize the performance index, FMFP repeatedly calls the subroutine SOLVE which, for a given set of independent variables, evaluates the performance index and its gradient.


Fig. F.1: Organization of the program ADOP.

Subroutine SOLVE:
SOLVE is the basic routine controlling the analysis portion of ADOP. It is called from FMFP and given the values of the independent variables; it then proceeds as follows:

1. Sets up frequency iteration loop for the frequency points specified.
2. Calls subroutine NOMA which sets up the circuit equations.
3. Calls subroutine ZDCOMP which decomposes the equations into an LU form.
4. Calls subroutine ZSOLV which solves the decomposed equations for circuit response.
5. Evaluates the performance index from circuit response.
6. Sets up the excitation to the adjoint equations.
7. Calls subroutine ZSOLITR which solves for adjoint network solution from the decomposed equations and adjoint network excitation.
8. Calls subroutine GREVAL which evaluates the performance index gradient.
9. Repeats iteratively over all frequency points.
10. Prints independent variables and corresponding solutions for the performance index and its gradient.

Subroutine NOMA:
Given the independent variables, NOMA sets up the complex variable nodal admittance matrix. NOMA is configuration dependent and must be changed for each configuration. A data statement is used to enter
all parameters pertinent to setting up the adnittance matrix. NOMA also sets up the partial derivatives of elements with respect to the independent variables and places them in labelled common; these are needed in the subroutine GREVAL.

Subroutine GREVAL:
Given the solutions to the original and adjoint circuits, along with the partial derivatives of the branch elements with respect to the independent variables; GREVAL evaluates the gradient components of the performance index.

## Subroutine 2DCOMP:

ZDCOMP decomposes the nodal admittance matrix, $Y$, into LU form using a Gaussian elimination

$$
\begin{equation*}
Y=L U \tag{F.1}
\end{equation*}
$$

Subroutine ZSOLV,
This subroutine solves the system of equations

$$
\begin{equation*}
L U_{\underset{\sim}{v}}=\underset{\sim}{\mathbf{i}} \tag{F.2}
\end{equation*}
$$

where $\underset{\sim}{v}$ is the vector of node voltages and $\underset{\sim}{i}$ is the current source vector set up in ADOP.

## Subroutine ZSOLTR:

Recognizing that the nodal admittance matrix of the adjoint network, $\hat{Y}$, is given by

$$
\begin{equation*}
\hat{Y}=Y^{t}=(L U)^{t}=U^{t} L^{t} \tag{F.3}
\end{equation*}
$$

## ZSOLTR solves the system of equations

$$
\begin{equation*}
u^{t} L^{t} \hat{v}=\hat{i} \tag{F.4}
\end{equation*}
$$

where $\hat{v}$ and $\hat{i}$ are the node voltages and current excitation for the adjoint network.

APPENDIX G

LISTING OF THE PROGRAM ADOP

## PRCGRAN AECP（INFLT，UUTFLT）

            DATA NC,NCLT,CASPIが12,it.1.
    ```
1 AFP,(WF(I),l=1,1し)/16, こ.U...C1,.1,.2,.25,.3,.34,.37,.4,.421,
2 hT/lC.,5.,4.,3......l., l., l., l.,l.l,
3 hトA/C.0,.C1,.1,.2,.3,.4,.45,.5,.56,.6,.65,.7,.75,.8,.9/
```

C
$N=11$
C
5 REAO $t,(X(1), I=1, N)$
6 FORNAT（8FIC．5）
IF（XI）．LT．C）GCTC 4
C
PRINT 13．GASF
13 FORMAT（ICX，7REASP＝，ELE．4／／／）
SET LP CIRClit excitaticn
DC $1 J=1, N C$
$1 C(J)=(C . C, C . C)$
$c(1)=(2 C ., C . c)$
C
EPS $=1 C . * *(-\varepsilon)$
LINII＝2CC
EST $=0$ ．

PRINT 2，F，（I，X（I），I，（I）I I＝1，N）
2 FORNAT／5X，14FRFTLFAEO F＇CIN1／／／ICX，EHERFCF＝ELL．5／／（I）X，IRX，Iク，
1 3t＝，E12．E，10X， 1 FCRAC．IL，？$=$ EEL2．511
PRINT 3，IFR

22 CCNTINLE
PRINT 2C
20 FCRNAT（5X，Z2FFFEG RESPCNSE FCF RFTURNEC FCINT／／／／／1：X，＋FFRFO，

OC 21 I＝1，15
$n=n f \Delta(1)$
CALL NCNA（N，X）
call zcccnf
CALL 2SCLV
AVR＝rital（VINClI））
AVI＝ameciv（nctit））

PHASt＝AIGAㄷ（AVI，RVD）



21 ccntinue
PRINT 2C2

GCTC 5
4 CCNTINLE
ENC
SUBRCLTINE FMFF(FLNCT, N,X,F,G,EST,EPS,LINIT,IER,H)

## SUERCUTINE FNFF

PUFPCSE
to finc a lecal mininun cf f flacticn of steval vafiariles by tre mithel of fleichfag and fohele

LSACE

cescrifticn cf faranetefs
funct - lesefrnritten slercltine ccncerning the function tio be Nininizec. It mLst eg cf the forn SLERCUTINE FLNCT(N,ARE, NAL, SPAD)
anc must strve ife flllching purpose
FCR EACH $n-E I N E A S I C A, A L$ ARGLAERT VECTCK APG, functicn valle fac graclent vector mlst be comfuted ANC, BN FETLRA, STCREC IN VAL ANO GHAE KESPECTIVELY
N - numef cf variaeles
x - vector cf cinensich a containing the initial arclment hherf the iteraticn startse in returin, $X$ fCLCS THE ARGLNENT CCKPESPOINING TS THE ccnfutec miningn flactica bilut
F - SIACLE VAKIARLE CCATAIAIAC THE MIMINUM FJNCTIUN VALUE CN FETLRA, I.E. F=F (X)
G - VECIUR CF CINFASICA C CNTAINIM, the GRADIENT vectick correspcicina te the manimum on rfituring I.E. $G=C(x)$.
est - is an estinate cf tre mininua functicn value.
EPS - TESTVALLE REPRESEATIAG TFE EXPECIED ABSCLUTE ERROR. A REASCAMELE CFCICE $1 S 10 * *(-\circlearrowleft)$, I.t. scmenhat greater tran lC**(-D), where o is the AUNBER EF £IENIFICANT CIGITS IN FLUATING PCINT REFRESEAIATICN.
linit - naximum numeer cf iteraticas.
IER - ERRCR paraneter
IER = O means cenvergence has ustained
IER = 1 means nc corvefeence ia limit iterations
IER $=-1$ NEANS ERRCRS IN GFEDIENT CALCLLATIOi
IER $=2$ NEANS LINEAR SEARCF TECHMIMLE INDICATES IT IS LIKELY trat trere ExiStS nig NIMIMJ.
H - inGRKING STCKAGE CF CINENSICN iN*(N+7)/2.
REMARKS.





```
A tclerffle rance cf arclment． IER＝ 2 NAY CCCLF ALSC IF Itr．IATE！．Vi．l．WHi：2E F INCREJSES IS SNALL ANE IFF JNITIIL Arisun！NI wAS
```



``` MININUN hAS CVLKLEAPEC．THIS IS JUE TO THE SEAKCH TECFAIGLE WHICF CCUBLES TFE STEFSILE UNTIL A PCIAT IS FCLIC where ItE FLNCTICA INCFEASES．
SURRCUTINES ANC FUNCIICA SLPFRCGRANS FEQUIALD FLNCT
```


## NETHCC

```
THE NETHCL IS DESCRIEEC IN THE FCLLCinING AFTICLE R．FLETCFER AND N．J．C．PChELL，A RAPID UESCENT METHDD FER NININIZATICA． CCMFLTER JCLKNAL VCL．E，ISS．2，ICEコ，PP．163－15G．
DINENSICNFC CUNNY VARIAELES
DINENSICN H（1ヒヒ），X（15），C（15），XCトC（15），ASIHX（15）
C
C InTERFELATICN LINIT
INTLT＝ \(1 C\)
C
C DIACNCSTIC KEYS
C
C
C CCNFUTE FUNCTICN VALUE ANC GRACIENT VECTOR FER INITIAL ARGURENT
PRINT ICOI
1001 FCRMAT（ \(10 \times 12\) FINITIAL PCINT／）
CALL FUNCT（N，X，F，（C）
C reset iteraticn cuunter anc generate ilentity mateix
\(I E R=C\)
KCLAT \(=C\)
N2 \(=\mathrm{N}+\mathrm{N}\)
N3＝へこ
\(\mathrm{N} 2 \mathrm{I}=\mathrm{N}\) こ +1
\(1 K=\mathrm{N} 31\)
DC \(4 J=1, N\)
\(H(K)=1\) 。
\(N J=\Lambda-J\)
IF（NJ）5，5， 2
2 DC \(3 L=1, \Lambda J\)
\(K L=K+L\)
\(3 H(K L)=C\) 。
\(4 K=K L+1\)
C save flnctich value, arelnent vectgi fac gracient vectcr.
        OLCF=F
        DC S J=1, \(\Lambda\)
        \(K=\mathrm{N}+\mathrm{J}\)
        \(H(K)=C(J)\)
        \(K=K+N\)
        \(H(K)=X(J)\)
    C

        \(K=J+N\) ?
        \(T=0\).
        DC B L=1; n
        \(T=T-G(L) *+(K)\)
        IF(L-J)6.7,7
        \(6 K=K+\Lambda-L\)
        GO TC 8
        \(7 \mathrm{~K}=\mathrm{K}+1\)
        8 CONTINしE
        S \(H(J)=T\)
        PRINT SC, (I, \(\mathrm{F}(1), I=1, \mathrm{~N})\)

    PRINT 81

                    Check htetrer flncticn hill eecresse stepping alcng h.
    \(D Y=0\).
    HNRN = C.
    GNRN = C.
    calculate cirectichal derivative anc testvalues for oipection
    vectcr \(f\) anc graclent vector e.
        DO \(10 \mathrm{~J}=1, \mathrm{n}\)
        HNRN=FARN+CES(F(J))
        GNRN=CAKM + LES(C(J))
    10 DY=CY+H(J)*た(J)
        REFEAT SEARCF IN DIKECTICN CF StEEfESt dEjCEMT if CIRECTIOAAL
        cerivetive jppears tc ee pcsitive cr zero.
        IF(CY)11, E11, E11
            REFEAT SEARCF IN difecticn cf steffesi descent if cirection
            vector his snall cinfagec tc gracient vectur g.

            SEARCF MININLN ALUNC cifectign f
            SEARCF ALCAC F FCR FESIIIVE CIFICIICAAL DERIVATIVE
        \(12+Y=F\)
        ALFA=え。* (EST-F)/CY
        \(P C=.249\)
        DC \(121 \mathrm{~J}=1, \mathrm{~N}\)
        IF(X(J) .EG. こ.) CCTO \(<1 \geq 1\)
        AStX(J) \(=\operatorname{ACS}(+(J) / x(J))\)
        GOTC 121
2121 AStX(d) \(=C\).
```

    121 CCNTINUE
        ETA = O.
    DC 1211 K=1,N
    ASF = ASFX(K)
    IFIETA.CT. ASFI CCTC IELI
    ETA=\DeltaSF
    1211 CCNTINUE
AMECA = PC/ETA
PRINT 1<2, AI.FF, AN!OUA

```

```

    l
        3コト--------------------------------------//
    C
C
C
C
IF(ALFA)15,15.12
13 IF(ALFA-\triangleNECA)14,15,15
14 ANECA=دLFA
15 ALFA=C.
C
C
16 FX=FY
UX=CY
C
C STEP ARGLNENI ALCNG F
DC 17 I=1,N
17 X(I)=x(I) +NNRCA*F(I)
C
C
USE ESTINATF FCR STEFSIZE CNLY IF IT IS PIISITIVE NNOO LESS THAN
PC/ETA. CTHERnISE TAKE FC/EIA \&S STEFSIZE.
SAVE FLNCTICN ANO dERIVATIVE VALUËg FCR OLD ARGUMENT
CLNPLTE FUNCTILA VALLE ANE GRALIENT FCR NEV GFGLNEAT
PRINY lCC2
1002 FCFNDT(EX,İHLIAEAF SEAFCF FCIAT/)
CALL FUNCT(N,X,F,C)
171 FY=F

```

C

REFEAT SFARCF ANE CCLPLE STEHSILE FER FURTHEK SEARCHES 20 ANECA＝小Nは［お＋ALFA ALFA＝ANECA

ENC CF SEARCF LCCP
TEFNINATE IF the ChANEE IA \(\angle R E L N E A T\) EETS VERY LARGE

```

21 1ER＝2 RETURA

```
```

C
C
C
C
22 INTCT = C
221 T = C
23 IF(ANECA)<4,3C1,24
24 INTCT = INTCT + 1
IF(INICT .GT. INTLT) CCTC.ZE2
Z=3.*(FX-FY)/ANECA+CX+CY
ALFA=ANAXI(AES(Z),fES([X),CES(CY))
DALFA=L/ALFA
DALFA=[ALFF*CALFA-LX/ALFA*[Y/ALFA
IF(CALFA)513,己巨,<E
25 W=ALFA*SGFT(CALFA)
ALFA=(CY+h-L)\#ENECA/(DY+Z.**h-CX)
DC 2c I=1,N
26 x(I)=x(I)+(T-ALFA)*+(I)
terminfte, if tre valle cF the actlfl functicn at x is less
THAN THE FLNCTICN VILLES fT THE INTERGAL ENOS. CTHERwISE RETUCE

```

```

        THE INTERPCLATICN. hHICH ENC-FCINI IS CHJOSEH DEPENOS GN THE
        value cf the flncticn ancilts gracient at x
            PRINT LCO?
    1003 FCRNAT(5X,IYFINTERFCLATICN PCINT/)
            CALL FLACT(N,X,F,C)
    201 IF(F-FX)27, <7, 己&
    27 IF(F-FY)3t,36,2&
    28 DALFA=0.
    CO 2G I=1,N
    29 DALFA=DALFA+C(I)*F(I)
    IF(CALFA) 3C,?2,2?
    30 1F(F-FX)?2, E1, ミ?
    31 1F(CX-CALFA)32,Zもミ,ミ2
    32 FX=F
        DX=CALFA
        T=ALFA
        AMBCA=ALFA
        GC TC 2?
    33 IF(FY-F)25, 24,?5
    34 IF(CY-CALFA)35, ECE,BS
    35 FY=F
        UY=CALFA
        AMBCA=ANECA-&LFA
        GCTC <2l
        ccmpute cifference vectchs Cf arglaent and gradient fócm
        ThC CCASEClitIvE iteraticas
    361 IFINKEYZ .EG. ll FRINT EEIC
    GCTC 3t
    3G2 IF(NKEYZ .EG. 1) FRINT בGZC
    GCTC \XiG
    3E3 IF(NKEY3.EG. 1) FFINT ミEZC
    ```

GOTC 26
3610 FORMAT（5X，17FANELA FQLALS LERC／／／5X，

3620 FCRMATIEX．IGFINTEFFCLAIICNLINIT／／／5X，

\(363 C\) FGKNAT \((5 X, 4 C F E G L A L\) ERRCKS ANC CIRECTICNAL DERIVATIVES／／／5X，

C
36 DU \(37 \mathrm{~J}=1, \mathrm{~N}\)
\(K=\Lambda+J\)
\(H(K)=C(J)-r(K)\)
\(K=\Lambda+K\)
\(37 \times C+G(J)=X(J)-1(K)\)
C
C
TEKNINATE，IF FLNCTICN トAS NCT EFCFEASED UURING LAST ITERATICO
IF（CLEF－F＋EPS） 51 ，コヒ， 3 E
C

C
TEST LENGTF CF ARGUNENT CIFFERENCE VECTDR ANO UIRECTICN VECTCR IF AT LEAST N ITERAIICNS FAVE EEEA EXECUTEU．TERNTAATE，IF
ECTH ARE LESS THAiv EFS
38 IER＝C
\(35 T=C\).
Z \(=\mathrm{C}\) 。
DC 4C J＝1，へ
\(T=T+\Delta E \leq(x C \vdash C(J))\)
\(402=2+\vdash(\Lambda+J) * \times(\vdash(J)\)
IF（KCLNT．CF．A •ANE．HARN．LE．EPS．AND．T．LE．EPSI GOTC 561
C
C TEFNINATE，IF NLNBEA CF ITERATIENS VCLLD EXCEED LIMIT
42 1F（KCLNT－LI＇IT）43，ごも，5C
C
C PREPARE UPCATING OF NATRIX
43 ALFA \(=\) C．
DC \(47 \mathrm{~J}=1, \Lambda\)
\(K=J+\Lambda 2\)
\(W=C\) 。
DC \(4 t L=1, N\)
\(K L=N+L\)
\(W=h+r(K L) \pm ト(K)\)
IF（L－J）44，45，4E
\(44 K=K+N-L\)
GC TC \(4 \epsilon\)
\(45 K=K+1\)
46 CCNTINLE
\(K=N+J\)
\(\Delta L F A=A L F A+h * F(K)\)
\(47 \mathrm{H}(\mathrm{J})=h\)
KEFEAT SEARCF IN UIKECTICN EF STEEFESI UEンCENT IF RSSULTS
ARE NCI SAIISFICTURY

471 PKINT 471C


GCTC 1
C
```

C
48 K=N31
DC 4S L=1,N
OO 4S J=L,N
H(K)= F(K) + XCFC(L)*xCFC(J)/2 - F(L)*F{J)/ALFA
49 K=K+1
GC IC 5
ENC CF ItERATICN LCCF
NC CCNvERGEACE AFtER, LINIt Iteraticns
50 IER=1
RETURA
C
C
C
511 PRINT E11C
GCTC El
512 PRINT 512C
GOIC :1
513 PPINT 51XC
GCTC 51
5110 FCRNAT(5x,49F[IRECTIGNAL RERIVATIVE NCANECATIVE - REINITIALIZE///
1 5X,3CH---------------------------------//)
512C FORMAT(EX,Z2FCIRECTICN VECICR SNALL/I/
1 5X,2CH----------------------------------//
513C FCFMATIEX,43+NEGATIVE SGRT fRGLNENT [LFING INTERPCLATION///
1 5X, 2CH--------------------------------//1
C
51 DO 52 J=1,N
K=\2+J
52 X(J)=+(K)
CALL FLACT(N,X,F,C)
C
C REFEAT SEARCF IN DIRECTICN CF STEEFESI DESCENT IF CERIVATIVË
C FAILS IC PE SUFFICIENILY S!AALL
IF(GARN-EFSISE,EE,E?
C
C tEST FCF REPEDIEC FAILLRE CF ItERAIICA
53 IF(IER)\&6,54,54
54 IER=-1
GCTC 1
55 IER=C
PRINT be2C
GCTC st
5620 FCRMAT(5x,22HGRACIENT LESS THMN EFS/I/EX,
l 2CF---------------------------------//1
C
561 PRINT 5t1C

```

```

        ITICNS///EX, コCト-----------------------------------/1
        56 PRINT 5EZ, KCLNT
    563 FCFNAT(EX,2CRNC. CF ITEFATICNS=,14/1/1)
        RETLRN
        ENC
        surrclitine sclve(n,xs,ef,efgrac)
    C

```

C
```

102 I=I +1
W=hF(1)

```
\[
V R(J)=R E A L(V(J))
\]

C

\section*{CALL zLCCNF}
scive fir ncel veltfces v
CALL ZSCLV
stcee feal fac inag farts cf \(v\) in vf fog vi
\[
00 \quad 1 C 2 J=1, \wedge C
\]

103 VI(J) = AINAC(V(J))

\section*{evallate ef ccafcnent fac acc tc ef}

GAIA \(=\) SGFT(VR(ACLT)**z + VI(NCLT)**
PHASE = \(\operatorname{ATANZ(VI(ACLT),V\therefore (NCLT))~}\)

\(E R=E R+E R C\)

C

104 CA（J）\(=(C . C, C . C)\) FAML \(=h T(I) *(1 .-G A S F / G \Delta I N)\) ．

sclve fer fejcint ncee veltaces va

\section*{CALL ZSCLTR}

STCRE FEAL ANC INAG FARTS CF VA．IN VAF ANU VAI
DC． \(1 C \leq J=1, N C\)
\(\operatorname{VAR}(J)=K E A L(V D(J))\)
105 VAI（J）＝AINAC（VA（J））
C
C
C
EVALLATE ERCRAC CLNFCNENT ANE ACL IE ERGRAD
CALL CREVAL（N，ERCFC）
DC 10t J＝1，N
1 C6 ERGRA［（J）＝EFCRA［（J）＋EFCFC（J）
C
GILC \(=\) CIIC + CCII
GI2C \(=\) CILC + CCIZ
\(C L E=C L G+C C L\)
TCCLG \(=\) TCCLE + CTCCU
C
IF（I．LT．NFF）GCTC IC2
PRINT 115，ER，（I，XS（I），I，ERGRAC（i），I＝1，M）
115 FORNAT（ICX，UHEFKER＝ELZ̈． \(5 / /(1 C X, 1 H x, 12,3 H=, E 12.5,10 X, 4 H G R A 1)\) ， 1 I2，2r＝，E12．51）
C
PRINT IIE，CIIC，EI2C，CLE，ICCLC



3
3CH－－－－－－－－－－－－－－－－－－－－－－－－－－－－－－－－－－－－1／1
RETURA
ENC
SURRCLTINE NCNA（N，XP）
C
SERIES－SERIES THIPLE
ncaa sets lf tre cenflex y－natpix in ye and yi hren given trf a－cinensicnil peraneter vectcf xp．the sutrrutine is cCAfiglraticn cefencent．

\section*{CCNfLEX \(A\)}

DINENSICN XP（N），YF（z，1z，12），YI（え，1z，1え）
CCNNCA／NATfIX／A（1二．12）／
1 FREG／h／CINY／AD，NCLT／FIRTIAL／PC（NI（G），HOGN？（G），PI）CNZ（G），
2
 Junc／vit

C

EGUIVfLEA(E (YF(1),YI(1),A(1))
C C C C
pafameter incefendent vflles are entefed through a [ata ceclaraticn.



3 FHCS,ASI,ASZ/.126..CE,.CEI
ASI, AS2 EGLAL CNE-rALF THE AREA PEf SGUARE fOK CII, giz
cefint faranetefs
GE1 \(=X F(1)\)
\(G M_{1}=X P(z)\)
GN2 \(=X F(E)\)
\(G L=X P(4)\)
\(E L 1=X F(E)\)
\(E L 2=X F(\epsilon)\)
\(E L 3=X P(7)\)
\(C L=.6+x P(E) \neq \# \bar{z}\)
\(C F=X P(S) * * 2\)
GII = GM1*VIト/(VCC+.7-VCE1) + XF\{1C)**
GI2 = GN2*VTR/IVCC+1.4-VCE1-VCE2) \(+X F(11) * * 2\)
NE1 \(=1\)
NE2 \(=1\)
NE3 \(=1\)
NR1 \(=1\)
NE2 \(2=1\)
NEZ \(=1\)
paraneter chpencent elenents
```

GE2 = CE1
GN3 = TCCLNTF - (CN1+(NZ)
GPII = CN1/EC1
GPI2 = GNz/OCz
GPI3 = GNE/PCE
GC1= EhNF*CN1
GC2 = EhNF\#CNE
GCZ = RhNF*CNz
VCE3 = E.] - VCE1 - VCEE
GF=CN2*VTF/(VCEI+VCE2-1.ム)
CEII = (1./EII)*(ASI/RFCS)*CCEI
CGI2 = (1./CIz)*(ASZ/Rt(S)*CCEz
SCLI =.S*NEL + .5\&NEl - .?
SCL2 = .S*NE2 + .E*NE2 - . E
SCL3 = .S*NE3 + . 5*NH3 - . 3
GCL = 32.3/(3.E/(\Sigma.t+SCLl+ELl) +..2/NE1)

```

```

GC3 = 32.3/(?.5/(z.t.+SCLI+ELZ) + . </NEE)
RXM1 =.21 + .¿/I(N1*VTt + L.Z)

```

```

RXN3 = . 21 + . </(CN2*VTF + 1.?)
GXI=NE1*(1.4<\#ELI + .IE)/FXNI

```

```

GX3 = NE3*(1.4<*EL? + .15)/RXN?
EAl=NE1*(.SE*ELI + © < T)
EA2 = NE2* (.9 E*FLZ + . ̈7)
EA3 = NEZ*(.GE\&ELE + - <丁)
BAl=(ELI+.8z)*(SCLL+.E2)-.(78

```

```

B^3=(FL\Xi+.日Z)*(S(L!+.\&こ) - .C7E
CAAI=(ELI+\overline{2.E)*(SCL1+1.4)}
CAA2 = (ELz+2.こ)*(SCLZ̈+1.4)
CAA3=(ELE+\ddot{C.E})*(SCLZ +1.4)
CATL=(ELI+3.7)*(SCLI+4.E) - . (4
CAT2 = (FL2+3.7)*(SCL`i+4.2) - .t4
CAT3 = (ELZ +3.7)*(SCL3+4.2) -..t4
CAPL=CAT1 - CAAI
CAPZ = CATE-CAAE
CAPZ = CATZ - CAAZ
CPII = CEE*EAI + 1PI\#CN1
CPI2 = CEE*EAZ + 1E2%GW2
CPI3 = CEE*EAE + TE3*CNE
CCB1 =.11/(VCE1-. こ)***.こ75
CCR2=.11/(VCE2-. ミ)**.ぐち5
CCE3 = . 11/(VCEZ-.ミ)x*.ぐ75
CUL = CCPI*EA1
CU2 = CCEZ\#EDZ
CU3 = CCPE\#EA?
CY1 = CCR1*(RA1-EF1)
CY2 = CCEZ*(EAZ-EAZ)
CYZ = CCEZ*(BAE-EAE)
CSl=.044/(VCC+1.1-VCE1)*\#. 34
CS2 =. C44/(VCC+1.7-VCE1-VCE2)**.34
CS3=.C44/(3.4)**. 34
CCS1= CA\&1*CS1
CCS2 = CAAZ*CSこ
CCS3 = CAAミ\#CSE
CCh1 =CAF1*CS1
CCh2 = CAF2*CSE
CCh3 = CAF3*CSE

```
```

PCGNE(1)= -1.
PCCM2(こ) = 1./EC2
PCENZ(z) = TEE
PDCN2(4) = VTF/(VCC+1.4-VCE1-VCEÉ)

```

```

    PCCNE(t) = EhmF
    PCCNZ(7) = -(CCIz/C12)*FCGNz(4)
    ```
        partial lefinatives horgt. cha.
    PCCN2(1) = 1./FC?
    \(\operatorname{PDCN}(2)=182\)
    PDCNZ(2) = VTF/(VCEI+VCFz-1.4.)

    PCGN \(3(5)=E n N F\)
    PARTIALS h.f.t.emitier strife lenctts
    PDELI(1) = NP1*1.4Z/KXN1
    PCELI(己) \(=C E E * N E] *\).S?
    PCELI(ミ) = CCP1*NE1*.S
    PDELI(4) \(=C\) CEl* (SCLI+.E2) - P[ELI(?)
    PCELI(E) \(=C \subseteq 1 \neq(S C L 1+1.4)\)
    PDELI(t) \(=\) CSl* \(2 . \varepsilon\)

    PCEL2(1) = NEぐ*1.4Z/RXNz
    PDELZ(2) = CEF*NEくか.9?

    PDEL2(4) = CCP2*(SCL2+.Eえて) - PCELz(3)

    PCELZ(t) = CSでえと.と

    PCEL3(1) = NEE\#].くこ/RXNミ



    PCELZ(5) \(=C S 2 *(S(L 2+1: 4)\)
    POEL3( \((6)=C \subseteq 3 * 2 . \varepsilon\)
    PDELき(7) = (ミ.5/ミミ.ミ)*(CCミ/(2.t+SCL?+EL?))**2
    partial lerivatives hof.t. cl
    PCXE = 2.*XF(E)
    partial cefinatives h.r.t. Cf
    PCXG \(=2 . * X F(c)\)
    partial gerivatives h.r.t. eil
    PCx10(1) = \(2 . \neq x F(1)\)
    PD×1C(2) \(=-(C(11 / E I 1) * F L \times I C(1)\)
        paktial cerivatives hor.t. eiz
    PCX11(1) =
    PDX11(2) \(=-(C C 12 / E I E) \times F[\times 11(1)\)
    clear y-natrix

C
    \(2 C 1 A(J, K)=(C . C, C . C)\)
define ncn－zerc elenents cf y－ndtrix
\(\operatorname{YR}(1,1,1)=C \leq+\in X 1\)
\(Y R(1,1,2)=-G \times 1\).
\(Y R(1,2,1)=-C \times 1\)
YR（1，2，2）\(=C \times 1+G F I 1\)
YR（1，2，a）\(=-\mathcal{C P I I}\)
YR（1，三， 2\()=-(G M 1+C P I 1)\)
\(Y R(1,3,2)=C N 1+C F I I+C C 1+C E I+C F\)
YR（1，2，4）＝－CCl
\(Y R(1,2,1 C)=-C F\)
YR（1，4， \(\bar{c})=C N 1\)
YR（1，4，2）\(=-(G N 1+(C 1)\)
\(Y R(1,4,4)=C C 1+C C 1\)
\(Y R(1,4,5)=-C C 1\)
\(Y R(1,5,4)=-C C 1\)
YR（1， 5,5\()=\) CCl \(+\mathbb{C} 11+\in \times 2\)
\(\operatorname{YR}(1, \varepsilon, \epsilon)=-E X \bar{z}\)
\(Y R(1, \epsilon, 5)=-\epsilon x_{z}\)
\(Y R(1, t, t)=\left(x_{2}+C F I 2\right.\)
YR（1，i，t）\(=C N 2\)
\(Y R(1,7,7)=C C 2+C(\overline{2}\)
\(Y R(1, \overline{7}, \varepsilon)=-C C \neq \ddot{z}\)
\(\operatorname{YR}(1, \varepsilon, 7)=-\in C 2\)
\(\mathrm{YR}(1, \varepsilon, \varepsilon)=C C 2+C I \bar{C}+\mathbb{C} \equiv\)
\(Y R(1, E, S)=-C X Z\)
YR（1，,\(~ \&)=-c X^{2}\)

YR（1，S，IC）＝－GFI3
YR（1，10，2）\(=-C F\)

\(Y R(1,10,1 C)=C N 2+C P I 3+C C Z+C E 2+C F\)
\(Y R(1,10,11)=-(C 2\)
\(\operatorname{YR}(1,11,5)=C N 2\)
YR（1，11，1C）＝－（CNミ＋GCミ）
\(\operatorname{YR}(1,11,11)=G C \equiv+C C 3\)
\(\operatorname{YR}(1,11,1 \bar{c})=-C C ?\)
\(Y R(1,12,11)=-C C 3\)
\(Y R(1,12,1 \bar{z})=C C \equiv+C L\)
C
```

YI(2,1,1)=n*CY)
YI (2,1,4)=-n*(Y)
YI(2,z,己)=n*(CFI) + Cl1)
YI(2,z,2)=-n*CFII
YI(2,z,4)=-n*Cl1
YI(2, ב,己)=-w*CFII
YI(2,彐,2)=h*(CFIL + CF)
YI(c,z,l0)=-n*C.F
YI(2,4,1)=-h*(Y)
Y I(2,4,<) =-n*Cll
YI(2,4,4)=n*(Cl) CCSI + (Y1)

```

YI（Z，－，¢ ）\(=n *(C C n l+C G I 1+C Y Z)\)
Y1（2，\(, 7,7)=-n * C Y\)
\(Y 1(2, t, 6)=h *(C F I 2+C L()\)
Y \(1(:, ~(, 7)=-n * C し 2\)

YI（ \(2,7, t)=-n * C L 2\)
Yl（2， 7,7\()=n *(C L 2+C C S Z+(Y 2)\)
\(Y 1(2, \varepsilon, E)=n *(C C h Z+C C l i ́+C Y Z)\)
YI（L．E，ll）＝－W＊CY
YI（2，\(\subseteq, c)=n \neq(C F I \underline{\underline{2}}+C L \equiv)\)
YI（2， \(5,1(C)=-h \# C F I 3\)
YI（2， 9,11\()=-h * C L 2\)
YI（2，10，2）\(=-h * C F\)
YI（2，lC，S）\(=-n * C P I \equiv\)
YI（2，1C，IC）＝h＊（CPI2＋CF）
YI（2，11，O）\(=-n *(Y\) ？
YI（2，11， 5\()=-\omega_{n} * C L 2\)
YI（2，11，11）＝n＊（CL \(+C C S 3+C Y \equiv)\)
YI（2，lえ，lく）\(=W *(C C h 2+C L)\)

RETLRA
ENE
suprcltine llcgnp

 THE［IACCNAL ELEWENTS CF L ARE STEREC IN THE A DIAGUN／LE THE OIAOUAJ ELENENTS CF L ARE UNITY ANC APE NET STCRED．
all cifecnal elenents ef a fre asslnec tu be nen－zerc
CCNFLEX \(\triangle\) ，fACTCR，MLLT
CCNNCN／NATRIX／A（1Z，12）／EINY／AD，NCLT
NCNINI \(=\) NC－1
CC ICC J＝1，NCNINI
\(F \triangle C T C F=(1, C, C, C) / A(J, J)\)
\(J P L U S 1=J+1\)
DC 1CC \(k=J F L L S 1, N C\)
MLLT \(=-A(K, J) \neq F A C T C K\)
\(A(K, J)=-N L L T\)
UC 1 Cし \(L=J F L L \subseteq 1, N C\)
\(100 A(K, L)=A(K, L)+\) MLLT 1 （J）L \()\)
RETLRA
ENC
SUERCLTINE zSCLV
CALCLLATES SCLLTICA FCR LIAEAK EGLATICA VINKHOWN VECTOK V FRON SCLRCE VECTCR C ANL LL EECCNFESTICA CF CUEFFICIENT MATRIX A． ALL VAFIAELES ARE C［NFLEX ANC A HAS EEEN DECDAPCSED BY SUBROUTI＇vE ZCCCNF。

CCNPLEX A，C，V，SLN
CCNNCN／NATRIX／A（1z，12）／SIE／V（1こう，C（1Z）／C［NY／ND，NGUT
\(V(1)=C(1)\)
```

        DC 2UC I=\Sigma,NC
        SUN = (C,C,C,C)
        ININI= l-1
        UC ICC J=1,INIAI
    LCOSUN = SLN+A(1,J)*V(J)
    20CV(I)=C(I)-SLN
    C
C
C
V(NC)=V(NC)/A(NC,ND)
CC 4CC K=\Sigma,NC
I=NC+1-K
IPLLSI=1+1
SUN = (C.C,C.O)
DC 3こC J=IFLUSI,NC
3COSLN = SLN+D(I,J)\#V(J)
400V(I)=(V(I) - SLN)/A(I,I)
RETLRA
ENC
SLBRCLTINE ZSCLIR
CALCLLATES SCLLTIUN FER LINEAR EGLATICN UNKNCWN VECTGC VA FRCM.
SCLKCE VECTCR CA ANE CCEFFICIENT NATRIX A-TFARSPCSE GLL VA~IABLOGS
ARE CCMFLEX ANE LU FCRN CF A ISLSEC AS FUUIVE EY SLIPCUTIME LDCOMP.
CCNPLEX A,CA,VF,SLN
CCMNCN/NATRIX/A(1E,12)/ASIC/VA(12),CI(12)/DIMY/NO,NCUT
C
VA(1)=C\&(1)/A(1,1)
DC 2CC I=\Sigma,NC
SLN = (C.C.O.C)
ININI= I-1
DC LCC J=1,ININI
1COSLN = SLN+A(J,I)\#VA(J)
2COVA(I)=(CA(I)-SLN)/A(I,I)
eACK SLESITLTE
OC 4CC K=Z,NC
I=NC+I-K
IPLLS1=1+1
SUM = (C.C,O.C)
DC ?OC J=IFLLS1,NC
300 SLN=SLN+A(J,I)\&VA(J)
4GCVA(I)= VA(I) - SLN
RETLRA
ENC
SLERCLTINE GREVAL(N,ERGFC)
SEFIES-SERIES TRIPLE
EVALLATES CCNPCNENT CF FLNCIICA GRACIENT AT FREG PCINT
ANC FFTLRNS VALLE IN N-EIMENSICNAL VECTOR ERGRC.
SLEKCLTINE GREVAL IS CGNFIGLPATILA LEFENDENT.
CINENSICN EFGRC(N)

```

```

    DGN1=(VF(2)-VR(こ))*(VAR(4)-VAF(3))-(VI(2)-VI(3))*
    1 (VAI(4)-VAI(2))
DGM2 = VF(\epsilon)\#V\&F(T) - VI(E)\#VAI(T)
OGN3 = (VF(G)-VR(IC))*(VAR(11)-VAR(IC))-(VI(O)-VI(10))*
1 (VfI(11)-VfI(IC))
DCPII=(VR(2)-VR(ミ))*(VAF(Z)-VAP(ミ))-(VI(2)-VI(3))*
1 (VAI(こ)-VA|(z))
OGPI2=VF(E)*VAF(C)-VI(E)*VAI(t)
UGPI3 = (VR(S)-VK(IC))*(VAF(G)-VAF(IC))-(VI(T)-VI(IC))%
1 (VAI(S)-V/I(1C))
OGC1=(VK(4)-VK(ミ))*(VAK(4)-VAK(ב))-(VI(4)-VI(3))*
1 (VAI(4)-VAI(E))
OGC2 = VR(7)*VAR(T) - VI(7)*VAI(7)
DGC3 = (VF(1L)-VR(1U))*(VAF(11)-VAF(LC))-(VI(11)-VI(IC))=
1 (VAI(11)-VA1(1C))
DGC1 = (VF(4)-VR(5))*(VAK(4)-VAF(E))-(VI(4)-VI(5))*
1 (VAI(4)-VA)(5))
DCC2 = {VR(7)-VR(\varepsilon))*(VFR(T)-VfF(E))-(VI(7)-VI(8))*
1 (VAI(7)-VAI(8))
CGC3=(VF(11)-VR(1z))\not=(VAR(11)-VAR(1z))-(VI(11)-VI(12))%
1 (VfI(11)-VAI(12))
DCPII= -h*((VR(2)-VR(Z))*(VAI(E)-VAI(Z))+(VI(2)-VI(3))*
1 (VAR(2)-VAR(3)))
DCFI2 = -h*(VR(E)*VAI(\epsilon) +VI(\epsilon)*VAR(\epsilon))
DCPI3 = -h*((VR(S)-VR(IC))*(VAI(S)-VAI(IC)) +(VI(G)-VI(IN))%
1 (VAR(S)-VAR(1C)))
DGII=VR(5)*VAR(E) - VI(5)*VAI(E)
DGI2 = VR(E)\#VAR(と) - VI(E)\#VAl(E)
DCCII = -h*(VR(E)*VAI(t) +VI(5)*VAR(5))
CCCI2 = -h*(VR(E)\#VAI(E) +VI(E)*VAR(E))
DGL = VR(12)*VAR(1こ) - VI(12)*VAI(12)
DGF=\VF(IC)-VR(E)I*(VAR(IC)-VAF(E)) - (VI(1O)-VI(3))*
1 (VAI(10)-VAI(2))
DGE1 = VF(ב)*VAR(E) - VI(E)*VAI(2)
DGE2 = VR(IC)*VAR(IC) - VI(IC)*VAI(IC)
DCF=-h*((VR(IC)-VR(Z))*(VaI(IC)-VدI(ミ))+(VI(10)-VI(3))*
1
(VAR(10)-VAF(Z)))

```

```

    OCXI={VR(1)-VR(z)|:&VAK(1)-VAK(z))-(VI(1)-VI(2))#
    1 (VAI(1)-VAJ(ट))
DGX2=(VF(5)-VR(E))*(VAF(E)-VAF(t))-(\I(5)-VI(6)):8
1 (VAI(5)-VA)(É))
DGX3 = (VF(B)-VR(c))=(VAF(E)-VAF(c))-(VI(8)-VI(G))*
1 (V\&I(\&)-VAI(S))
DCLI = -h*((VR(こ)-VR(4))*(VDI(z)-VAI(4)) +(VI(2)-VI(4))*
1 (VAF(2)-VAF(4)))

```

```

1 (VLF(<)-VAR(7)))
UCL3=-W*((VR(G)-VK(1)|))*(VAI(G)-VAl(1]))+(VI(c)-VI(11))\&

```
```

1 (vfF(q)-VAF(1L)))

```

```

1 (VAF(1)-Vi.F(4)))

```

```

1 (VAR(5)-VAF(j)))

```

```

1 (VAR(B)-VAR(11)1)
CCCS1= -h*(VF(4)*V:I(c) +V1(<)*V:R(4))
DCCS2 = -n*(VK(7)*VAI(7) +VI(7)*VなF(7))
CCCS3=-h*(VP(11)*Vi.l(11)+V1(11)*Vfir(11))

```

```

    OCCh2 = -h*(VR(E)*V:I(r) + V!(E)&Vかr(E))
    ```


EKCRC（1）＝LCE！＋LCL2



3 + C(FxF[CN? (E) + CCXEAF[CN2(4))
4 + CCCI]*F[じン](テ)



    \(3+\) CCF~PCCN3(三) + CCX2*PCCNZ(4))
    4 + CCCI2ヵFCGNくiつ)
    ERCRC(4) = CCL


    \(2+\) CCCI:FCRLI(i)





    \(2 \rightarrow\) CCC2*FCEL2(7)
    ERGRC(E) \(=\mathrm{FL} \times \mathrm{A} \times \mathrm{CCL}\)
    ERCFC(S) \(=\) FCXC*LCF
    ERERC(1C) \(=P C X I U(1): 1) \in 11+F C \times 1 C(2) \div C(G 11\)
    ERCRC(11) \(=P C X 1\) (i) \(2: D C 12+F[\times 11 \times C C E I 2\)
            ERFCF CERIVATIVE B.K.T. TCTAL CC CLFRENT

\(1+\operatorname{FCGN} 3(4) * G C X 3+F[C N 3(5) * C G C 2) / W T H\)

C
RETLRA
ENE

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[^0]:    *A single transistor stage is referred to as a common-emitter stage, even in the presence of series emitter feedback, if the transistor base and collector currents are defined, respectively, as the input and output currents of the stage. Such a stage is capable of providing both voltage and current gain and there is a phase inversion between input and output.

